

WaveMaster 8 Zi-B Oscilloscopes 4 GHz-30 GHz



Key Features

- Up to 30 GHz bandwidth and 80 GS/s sample rate
- Most advanced oscilloscope user interface makes configuring complex measurements easy
- The industry's only true hardware
 14.1 Gb/s serial pattern trigger
- Add the Teledyne LeCroy HDA125
 High-speed Digital Analyzer to
 create the most powerful, flexible
 mixed-signal test solution available
- Low Jitter Measurement Floor and exceptional timebase stability
- Comprehensive set of serial data analysis, debug, validation and compliance tools
- Integrated 50 Ω and 1 MΩ inputs for true connection and probing flexibility
- Integrated standard and custom measurements and math functions for unrivaled analysis capability
- Multi-lane serial data eye, jitter and crosstalk analysis

The WaveMaster 8 Zi-B combines the performance, signal fidelity and feature set needed for today's high-speed measurements with the ease-of-use of a standard benchtop oscilloscope. Featuring the highest-speed serial data triggers, the only complete multi-lane serial data analysis and eye diagram solution, and the most comprehensive set of compliance packages, the WaveMaster 8 Zi-B simplifies the most complex testing.

Exceptional Performance

With up to 30 GHz bandwidth, 80 GS/s sample rate, low noise, an extremely stable time base and a 14.1 Gb/s serial trigger the WaveMaster 8 Zi-B has the hardware performance to capture today's high-speed signals.

Most Advanced User Interface

Teledyne LeCroy's MAUI user interface puts the deepest measurement toolset of any oscilloscope at your fingertips. Coupled with the WaveMaster 8Zi-B's 15.3" high-resolution touchscreen, MAUI makes advanced analysis easy to set up and use. A flat menu structure puts the most common tools in the easiest reach. Sophisticated multi-grid displays are simple to configure. Vertical, horizontal and acquisition setting changes are made without obscuring waveform display.

Advanced Waveform Processing

A powerful PC with a 3.1 GHz quad core processor and up to 32 GB of RAM enables fast waveform processing for the most advanced analysis. User-defined mathematical functions and measurements are available natively, or through seamless integration with external environments like MATLAB.

Complete Characterization, Compliance Testing and Debug

The WaveMaster 8 Zi-B provides the most powerful analysis tools. SDAIII-CompleteLinQ simultaneously displays eye diagrams and breaks down jitter on four signals. EyeDrII and VirtualProbe options analyze lane interactions using S-parameter files. Crosstalk tools analyze amplitude noise. QualiPHY software simplifies and automates compliance testing and reporting for a wide range of serial data standards.

MAUI - THE MOST ADVANCED USER INTERFACE



MAUI – Most Advanced User Interface was developed to put all the power and capabilities of the modern oscilloscope right at your fingertips. Designed for touch; all important oscilloscope controls are accessed through the intuitive touch screen. Built for simplicity; time saving shortcuts and intuitive dialogs simplify setup. Made to solve; a deep set of debug and analysis tools helps identify problems and find solutions quickly.

Designed for Touch

MAUI is designed for touch. Operate the oscilloscope just like a phone or tablet with the most unique touch screen features on any oscilloscope. All important controls are always one touch away. Touch the waveform to position or zoom in for more details using intuitive actions

Built for Simplicity

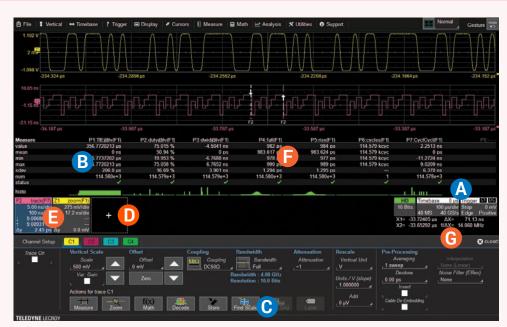
MAUI is built for simplicity. Basic waveform viewing and measurement tools as well as advanced math and analysis capabilities are seamlessly integrated in a single user interface. Time saving shortcuts and intuitive dialogs simplify setup and shorten debug time.

Made to Solve

MAUI is made to solve. A deep set of integrated debug and analysis tools help identify problems and find solutions quickly. Unsurpassed integration provides critical flexibility when debugging. Solve problems fast with powerful analysis tools.

MAUI with OneTouch

MAUI with OneTouch introduces a new paradigm for oscilloscope user experience. Dramatically reduce setup time with revolutionary drag and drop actions to copy and setup channels, math functions, and measurement parameters without lifting a finger. Use common gestures like drag, drop, and flick to instinctively interact with the oscilloscope. Quickly enable a new channel, math or measurement using the "Add New" button and simply turn off any trace or parameter with a flick of the finger. These OneTouch innovations provide unsurpassed efficiency in oscilloscope operation.



- A Channel, timebase, and trigger descriptors provide easy access to controls without navigating menus.
- B Configure parameters by touching measurement results.
- Shortcuts to commonly used functions are displayed at the bottom of the channel, math and memory menus.
- Use the "Add New" button for one-touch trace creation.
- Drag to change source, copy setup, turn on new trace, or move waveform location.
- Drag to copy measurement parameters to streamline setup process.
- **G** Drag to quickly position cursors on a trace.

SDA8ZI-B SERIAL DATA ANALYZER











WaveMaster 8 Zi-B

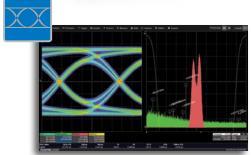
SDAIII Eye and Jitter Analysis

Extended Acquisition Memory

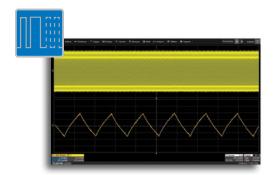
High-speed Serial Triggering



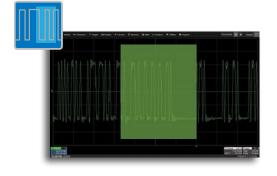
With its combination of high bandwidth, excellent signal fidelity, and the most complete toolset in its class, the WaveMaster 8 Zi-B is the ideal platform for high-speed serial data analysis. The SDA 8 Zi-B models have been specifically configured to handle today's most challenging serial data applications:



The SDA 8 Zi-B comes standard with the SDAIII core toolset, providing tightly-integrated and comprehensive eye diagram and jitter analysis for NRZ signals. SDAIII easily emulates complex clock recovery and PLL behavior, and quickly renders eye diagrams using all acquired unit intervals. Jitter analysis includes Rj - Dj separation, Tj extrapolation, measurements of DDJ, ISI, and Pj, and visualization using histograms, tracks, and jitter spectra.



With 64 Mpts on all four input channels, the SDA 8Zi-B doubles the WaveMaster's standard acquisition memory. Serial data analysis puts a particular set of demands on an oscilloscope's timebase capabilities. Decoding up to protocol level typically requires the acquisition of long waveforms. Likewise, slowly-varying physical-layer characteristics such as Spread-Spectrum Clocking (SSC) must be analyzed over periods of milliseconds.



The SDA 8Zi-B comes standard with a true hardware high-speed serial pattern trigger, to ensure capture of even the rarest pattern at up to 6.5 Gb/s. The trigger also natively triggers on 8b/10b and 64b/66b words, with corresponding decoders included in the SDA configuration. And if 6.5 Gb/s is not enough, the high-speed serial trigger can be upgraded to an industry-leading 14.1 Gb/s.

THE MOST CAPABLE HARDWARE PLATFORM

The WaveMaster 8 Zi-B is built on an exceptionally accurate acquisition system, with pristine signal fidelity and high timebase stability. Coupled with the most flexible set of inputs and the highest-performance serial trigger, it represents the most versatile platform in its class.

- Pristine high-bandwidth performance:
 - Up to 30 GHz bandwidth, 80 GS/s sample rate,
 512 Mpts of analysis memory on 2 channels
 - Up to 20 GHz bandwidth, 40 GS/s sample rate,
 256 Mpts of analysis memory on 4 channels
 - Exceptionally accurate and stable timebase -100fs (rms) timebase jitter
- Bandwidth upgrade capability from 4 GHz to 30 GHz to maximize investment leverage
- Hardware serial triggering up to 14.1 Gb/s
 - The highest speed true-hardware serial trigger provides capability for 80-bit NRZ serial pattern triggering, 8b/10b and 64b/66b symbol triggering.
 - Teledyne LeCroy's true hardware trigger means even infrequently-occurring patterns can be reliably triggered on and captured. Competing software "serial triggers" risk missing rare events.
 - A 6.5 Gb/s serial trigger is included standard with SDA 8 Zi-B models, upgradeable to 14.1 Gb/s.
 Either serial trigger may be added to
 WaveMaster 8 Zi-B and DDA 8 Zi-B models.
- The only high-bandwidth oscilloscope to support both 50 Ω and 1 M Ω inputs on the same instrument without the use of cumbersome external adapters.
- Add HDA125 High-speed Digital Analyzer via the integrated LBUS connector to give 18 digital channels at 12.5 GS/s each - for the most advanced mixed-signal test system available.



SUPERIOR ANALYSIS AND INSIGHT



The WaveMaster 8 Zi-B's MAUI advanced user interface combines the deepest toolset with simple operation, making it easy to configure sophisticated measurements. The operating software is seamlessly integrated with the hardware platform, providing the best responsiveness and ease of use in its class.

- The most complete set of measurement and analysis tools in the industry leverage powerful processing capability to provide deeper insight in less time.
- Intel® Core™ i7-4770S Quad-core, 3.1 GHz (per core, up to 3.9 GHz in Turbo mode) CPU with 8 GB of RAM (upgradeable to 32 GB)
- High resolution 15.3" WXGA widescreen color touch screen display.
- X-Stream II streaming architecture 10-100 times faster analysis and better responsiveness than other oscilloscopes
- QualiPHY serial data compliance packages speed up testing times and reduce complexity with fully automated compliance packages for PCI Express®, DDR memory, USB 3.0, and many other standards.
- Crosstalk and Vertical Noise Analysis
- SDAIII "LinQ" options provide four simultaneous eye diagrams and jitter calculations for multi-lane serial data link analysis, or for single-lane, multiple location analysis
- Eye Doctor™ II and Virtual Probe Signal Integrity Toolsets provide real-time de-embedding, emulation, and equalization on serial data channels and complex networks
- 325 MB/s data transfer rate from oscilloscope to PC with Teledyne LeCroy Serial Interface Bus (LSIB) option

THE MOST FLEXIBLE MIXED-SIGNAL SOLUTION

Key Features

- 12.5 GS/s sampling rate for 80ps timing accuracy
- 3 GHz leadset for capturing digital signals up to 6 Gb/s
- Add high-speed mixed-signal capability to your Teledyne LeCroy high-bandwidth oscilloscope
 - LBUS connection for precise timing synchronization
 - USB 3.1 for fast data transfer
- Unique QuickLink probing system
 - Differential solder-in tips with
 9-inch lead simplify access to
 difficult test points
 - Ultra low loading for superior performance
 - 8 GHz bandwidth tips are compatible with both HDA digital leadset and Teledyne LeCroy WaveLink differential analog probes for unmatched acquisition flexibility



The HDA125 transforms your Teledyne LeCroy oscilloscope into the highest-performance, most flexible mixed-signal solution for high-speed digital debug and evaluation. With 12.5 GS/s digital sampling rate on 18 input channels, and the revolutionary QuickLink probing solution allowing seamless transitions from digital to high-bandwidth analog acquisitions, validation of challenging interfaces such as DDR4 has never been simpler or more comprehensive.

Complete Embedded System Debug

Modern embedded systems increasingly utilize high-speed digital buses, posing new and evolving challenges to validation and debug engineers. While analog signal-integrity characterization is a critical part of this process, the ability to decode and trigger on related digital buses is becoming a vital capability. The HDA125 High-speed Digital Analyzer addresses this need with the most flexible solution available.

Unique probing solution

One of the most challenging aspects of high-speed embedded test is simply getting the signals from the system under test to the instrumentation with

sufficient fidelity. The HDA125 is built around Teledyne LeCroy's revolutionary QuickLink probing concept - enabling high signal quality, easy access to remote test points, and simple transitions from digital to analog probing.

Enhanced DDR Debug

Teledyne LeCroy already offers the industry's only dedicated DDR Debug Toolkit, designed to simplify challenging memory interface validation. Adding the HDA125 allows the DDR command bus to be directly acquired and integrated into the analysis, enabling advanced command triggering and sophisticated, searchable bus state viewing.

STANDARD SPECIFIC SOLUTIONS



The SDA 8Zi-B is configured specifically for testing serial data signals. With high-speed serial triggering capability and the most comprehensive analysis software, the SDA 8Zi-B is the obvious choice for the most challenging test and debug tasks:

DDR Memory

Verifying DDR memory operation is one of the most common challenges in high-speed electronics today. The SDA 8Zi-B is the ideal platform for validating and debugging DDR implementations.

- Teledyne LeCroy's unique DDR Debug toolkit is the ultimate DDR analysis package. Perform Read/Write burst separation and display eye diagrams, jitter analysis, and measurements specific to DDR, allowing for a quick understanding of system performance with a push of a button.
- QualiPHY-DDR packages perform automated JEDEC compliance testing for DDR2, DDR3, DDR4, LPDDR2, and LPDDR3.
- Unique probing solutions solve the challenge of probing DDR signals.

PCI Express®

The SDA 8Zi-B is the basis of the industry's most complete PCI Express test solution:

- Automated transmitter and receiver compliance testing using QualiPHY.
- The only certified solution for Link Equalization testing (required for PCI-SIG compliance) using the PeRT³ Phoenix.
- Comprehensive PCIe debug capability:
 - SDAIII eye and jitter analysis with built-in PCIe clock recovery emulation and eye masks
 - Protocol-layer decode correlated to physical-layer traces
 - PCle-specific measurements.

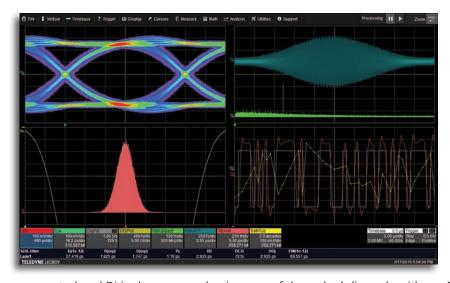
Automated Compliance Testing

Teledyne LeCroy's QualiPHY software is the ideal solution for physical layer compliance testing, making it easy to produce a comprehensive report of test results including screenshots. QualiPHY reduces the time and effort needed to perform compliance testing on a wide array of serial standards including:

- PCI Express (1.0, 2.0, 3.0)
- USB1, USB2, USB 3.0, USB 3.1
- DDR2, LPDDR2, DDR3, LPDDR3, DDR4
- SAS2, SAS3, SATA
- MIPI D-PHY and M-PHY
- 10/100/100 BASE-T,
 10GBASE-T,
 10GBASE-KR, SFI
- HDMI 1.4, HDMI 2.0, DisplayPort, eDP
- MOST50, MOST150, BroadR-Reach



SDAIII SERIAL DATA ANALYSIS TOOLKIT



The Teledyne LeCroy SDAIII-CompleteLinQ
Serial Data Analysis products include
multi-lane eye and jitter analysis, LaneScape™
comparison modes, vertical noise
measurements, and crosstalk analysis tools.
These capabilities provide the deepest insight
into the behavior of multi- or single-lane serial
data systems.

SDAIII Core Toolset

Teledyne LeCroy provides the most complete toolset in the industry for jitter measurements and eye diagram/jitter analysis. Rj and Dj are

separated and Dj is decomposed using one of three dual-dirac algorithms. Eye diagrams containing all acquired unit intervals are rendered 10-100x faster than competitive systems. Eye diagram analysis tools, such as the extrapolated IsoBER plot, aid insight. Multiple additional tools, such as Tracks, Histograms, and Spectrum waveforms, enhance the understanding of jitter causes. Sophisticated pattern analysis tools like Intersymbol Interference (ISI) measurements and plots provide deep insight into Data Dependent Jitter (DDj) behavior.

Measure up to 4 Lanes Simultaneously

"LinQ" products provide extensive multi-lane analysis capabilities. Quickly understand lane-to-lane differences in jitter measurements, eye diagrams, and jitter analysis. Perform aggressor on/off analysis, and see the results from both scenarios simultaneously. Save the analysis of a particular scenario to the Reference Lane, and configure a LaneScape™ Comparison mode to compare the Reference to either one, two or all lanes. Each "lane" can be a different serial data lane, or a different analysis of data from a single serial data lane - ideal for comparing different

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equalization schemes (using Eye Doctor II option) or examining system behaviors at different locations in the link (using probes or the VirtualProbe option).

Learn More: teledynelecroy.com/SDAIII

CompleteLinQ Does it All

The CompleteLinQ user interface framework provides easy access to all features described above, and also integrates EyeDoctorII and VirtualProbe capabilities for Tx/Rx equalization and fixture/channel de-embedding/emulation. Order SDAIII-CompleteLinQ to equip your oscilloscope with all of Teledyne LeCroy's Serial Data Analysis and Signal Integrity tools.



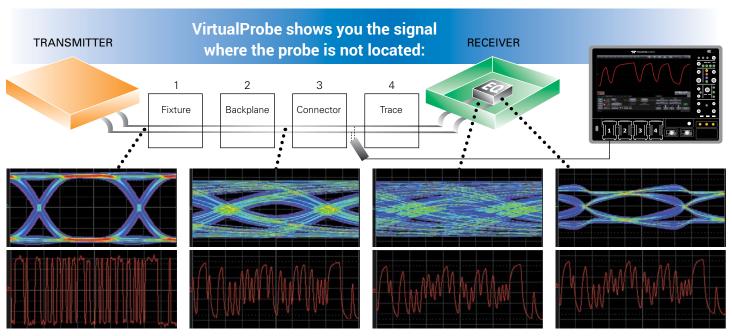
ADVANCED SIGNAL INTEGRITY TOOLS

EyeDoctorII

Many high-speed measurements require removing the effects of a fixture, applying a channel model, and emulating the operation of a receiver equalizer on an acquired signal. The EyeDoctorII package includes easy configuration of basic de-embed/emulation scenarios, CTLE, DFE and FFE equalizers, and transmitter emphasis/de-emphasis.

VirtualProbe

The VirtualProbe package expands the capabilities of EyeDoctorII. Configure a multi-block circuit using S-parameters, and VirtualProbe will display the signal as it would appear before or after any block in the circuit. The electrical behavior of a block to reflect and transmit signals can be included, added or removed. Probe loading effects can also be removed.



mitter with the fixture present, and then de-embed its effects form the measurement.

Virtually probe the signal at the trans-

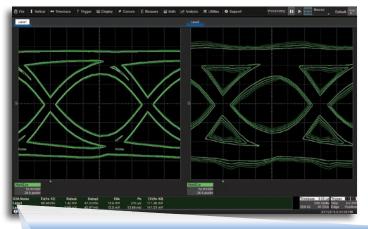
View the signal between structures to understand losses, ISI and crosstalk caused by backplanes, interconnects and connectors.

See what the eye looks like at the receiver - even if it is not in reach of a differential probe.

Use EyeDoctor to open the eye by modeling CTLE, FFE and DFE equalizers used by your receiver.

Vertical Noise and Crosstalk

The Crosstalk and CrossLinQ packages provide vertical noise measurements and crosstalk analysis tools for



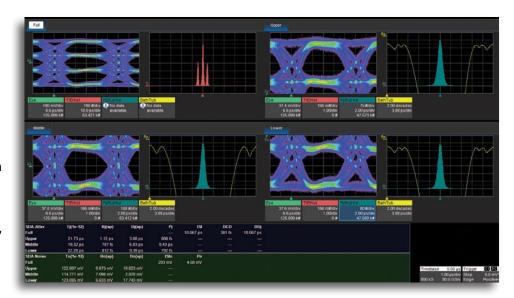
complete aggressor/victim analysis. Use one of three dual-Dirac models to measure and separate noise into total (Tn), random (Rn) and deterministic (Dn) components, and further decompose Dn into Intersymbol Interference Noise (ISIn) and Periodic Noise (Pn). Only Teledyne LeCroy performs this analysis on real-time oscilloscopes. Similar to jitter analysis, noise can be viewed as a noise track, histogram and spectrum, providing insight into the vertical noise resulting from coupling to other active serial data lanes or other interference sources. The Crosstalk Eye shows the probabilistic extent of noise both inside and outside the eye, quickly showing the impact of excessive noise that is not possible to see in a traditional eye diagram.

SDA Noise	Tn(1e-12)	Rn(sp)	Dn(sp)	ISIn	Pn	
Lane1	65.94 mV	1.32 mV	47.41 mV	12.9 mV	214 µV	
Lane2	96.52 mV	3.59 mV	45.97 mV	12.9 mV	13.69 mV	

PAM4 SIGNAL ANALYSIS

Key Features

- PAM4 Eye Diagrams
- Eye Height and Eye Width @BER for upper, middle and lower eyes
- Tj, Rj, and Dj Jitter Decomposition
- Tn, Rn, and Dn Noise Decomposition
- IsoBER Contour Plot
- Jitter and Noise Tracks, Histograms, and Spectra
- Level Measurements
- LaneScape™ Mode Comparisons
- Equalization of PAM4 Signals using EyeDoctorII
- Simulation of PAM4 Waveforms with Jitter Sim



PAM4 represents a new step in the evolution of serial data signaling formats, overcoming some fundamental limitations of traditional NRZ signaling. But with new signal types come new measurement needs. Teledyne LeCroy's PAM4 analysis package meets these needs by leveraging industry-leading eye, jitter, and noise analysis capabilities to fully characterize PAM4 signals.

PAM4 signaling is being closely considered by standards organizations as the successor to NRZ signaling for the next generation of communication standards.

As with NRZ signal analysis, engineers working with PAM4 require sophisticated tools to measure how effects such as frequency-dependent losses and ISI impair signals and close the eye openings. But unlike NRZ signaling, the science of measuring PAM4 signals is new and evolving quickly to keep pace with the rapid advances in this technology.

Teledyne LeCroy's PAM4 Signal Analysis gives high-speed design engineers the same familiar NRZ analysis toolkit, but with sophisticated new measurement algorithms specific to the complexities of PAM4.

The PAM4 Signal Analysis package performs a complete analysis of PAM4 waveforms. It analyzes the signals, creates eye diagrams, measures eye closure in voltage and time, and predicts closure as a function of BER. It is fully integrated into Teledyne LeCroy's sophisticated MAUI user interface, allowing for advanced capabilities like channel emulation and de-embedding.

COMPLETE SERIAL DATA TEST

Data Rate Configuration Chart

Standard	Bit Rate	Minimum Bandwidth	Recommended Oscilloscope
PCI Express Gen1	2.5 Gb/s	6 GHz	SDA 806Zi-B or Above
InfiniBand	2.5 Gb/s		
Serial Rapid I/O	2.5 Gb/s		
DisplayPort 1.1	2.7 Gb/s	0.011	
SAS Gen1	3 Gb/s	8 GHz	SDA 808Zi-B or Above
Serial Rapid I/O	3.125 Gb/s		
XAUI	3.125 Gb/s		
HDMI 1.4	3.4 Gb/s		
SATA Gen2	3 Gb/s	10.011-	
DDR4	4 GT/s	10 GHz	
Fibre Channel 4GFC	4.25 Gb/s		
Serial Rapid I/O	4.25 Gb/s		
InfiniBand	5 Gb/s		SDA 813Zi-B or Above
PCI Express Gen2	5 Gb/s	13 GHz	SDA 813ZI-B OF ADOVE
PCI Express Gen3	8 Gb/s		
Serial Rapid I/O	5 Gb/s		
USB 3.0	5 Gb/s		
DisplayPort 1.2	5.4 Gb/s		
GDDR5	6 Gb/s		
SAS Gen2	6 Gb/s		
SATA Gen3	6 Gb/s	16 GHz	SDA 816Zi-B or Above
Serial Rapid I/O	6.25 Gb/s	16 GH2	SDA 610ZI-B OI ADOVE
QPI (Quick Path Interconnect)	6.4 Gb/s		
USB 3.1	10 Gb/s		
10GBase-KR	10.3125 Gb/s	20 CH-	SDA 820Zi-B or Above
SFI/SFP+	10.3125 Gb/s	20 GHz	SDA 820ZI-B OF ADOVE
CEI-11	11 Gbps	2E CH-	CDA 0257: D av Abassa
SAS12	12 Gb/s	25 GHz	SDA 825Zi-B or Above
InfiniBand	25.78125 Gb/s		SDA 830Zi-B,
CEI-25/28	25-28 Gb/s	30 to 100 GHz	LabMaster 9 Zi-B or LabMaster 10 Zi up to 100 GHz

PeRT³ Phoenix – Protocol Enabled Receiver and Transmitter Tolerance Tester

Modern high-speed electronics test demands a set of instruments that goes beyond the oscilloscope, for applications such as receiver tolerance testing and interconnect characterization. Teledyne LeCroy addresses these challenges with innovative instruments which are both powerful and easy to use, simplifying test and reducing time-to-market.

Modern serial data standards such as PCI Express 3.0 require negotiation of equalization parameters to ensure interoperability. Truly testing a receiver's operation demands an instrument which perform more than just the basic BERT functions of pattern generation and error detection. Teledyne LeCroy's PeRT³ is the industry's first Protocolenabled Receiver Tester, a totally new class of instrument designed to overcome these difficult test challenges. The combination of the PeRT³ and the SDA 8Zi-B represents the most complete serial data test system available.



WAVELINK PROBE SYSTEMS

WaveLink High Bandwidth Differential Probes

Ultra-wideband Architecture with Superior Signal Fidelity

Teledyne LeCroy's WaveLink® high bandwidth differential probes utilize advanced amplifier architecture to achieve superior analog broadband performance. Exceptional noise characteristics mean the combination of the probe and the oscilloscope results in measurement performance that is nearly identical to that of a cable input.

Versatile High Bandwidth Probe Tips up to 25 GHz

Solder-In tips with 25 GHz bandwidth and system (probe + oscilloscope) rise times equal to that of the oscilloscope alone. The most compact positioner tip browser with bandwidth up to 22 GHz makes probing in confined areas easy.

Superior Probe Impedance Minimizes Circuit Loading

Circuit and signal loading is reduced by more than 50% compared to competitive probes. In the mid-band frequency range, the difference is even more apparent.



D2505-A-PS 25 GHz probe system with Solder-In lead and browser positioner tip.

	D1305-A-PS	D1605-A-PS	D2005-A-PS	D2505-A-PS
Bandwidth	Dxx05-SI and Dxx05-PT Tips 13 GHz	Dxx05-SI and Dxx05-PT Tips 16 GHz	Dxx05-SI and Dxx05-PT Tips 20 GHz	Dxx05-SI Lead 25 GHz Dxx05-PT Tip 22 GHz typical 20 GHz guaranteed
Rise Time (10-90%)	Dxx05-SI and Dxx05-PT Tips 32.5 ps (typical)	Dxx05-SI and Dxx05-PT Tips 28 ps (typical)	Dxx05-SI and Dxx05-PT Tips 20 ps (typical)	Dxx05-SI Lead 17.5 ps (typical) Dxx05-PT Tip 19 ps (typical)
Rise Time (20-80%)	Dxx05-SI and Dxx05-PT Tips 24.5 ps (typical)	Dxx05-SI and Dxx05-PT Tips 21 ps (typical)	Dxx05-SI and Dxx05-PT Tips 15 ps (typical)	Dxx05-SI Lead 13 ps (typical) Dxx05-PT Tip 14 ps (typical)
Noise (Probe)	< 14 nV/√Hz (1.6 mV _{rms}) (typical)	< 14 nV/√Hz (1.8 mV _{rms}) (typical)	< 18 nV/√Hz (2.5 mV _{rms}) (typical)	< 18 nV/VHz (2.8 mV _{rms}) (typical)
Input Dynamic Range Input Common Mode Voltage Range			.0 V) (nominal) nominal)	
Input Offset Voltage Range		±2.5 V Differe	ential (nominal)	
Impodance	Dv	v0E-CLI 444: 200 O 4	t 6 CUz 525 O at 12	CLIZ

Impedance (mid-band, typical) **Dxx05-SI Lead:** 300 Ω at 6 GHz, 525 Ω at 13 GHz, 600 Ω at 16 GHz, 300 Ω at 20 GHz, 120 Ω at 25 GHz **Dxx05-PT Tip:** 160 Ω at 6 GHz, 450 Ω at 13 GHz, 240 Ω at 16 GHz, 210 Ω at 20 GHz

Other WaveLink Probing Solutions

With bandwidths from 4 GHz to 13 GHz, wide input dynamic range, exceptionally low loading and versatile tip selections, the Medium- and Low Bandwidth WaveLink Differential Probe Systems are ideal for many applications - including the often-challenging probing of DDR memory signals.

WaveLink Low Bandwidth Differential Probes

- 4 and 6 GHz models
- Solder-In, Browser,
 Quick Connect,
 Square Pin, Positioner Tip,
 QuickLink adapter and
 HiTemp Cables



WaveLink Medium Bandwidth Differential Probes

- 8, 10, and 13 GHz models
- 3.5 V_{p-n} Input Dynamic Range
- ±4 V Offset
- Solder-in, Positioner (Browser), Square Pin, QuickLink adapter, Hi-Temp cables, and SMA/SMP lead connection



BROAD RANGE OF PROBING SOLUTIONS

WaveMaster 8 Zi-B oscilloscopes support a broad range of probes for a variety of applications.

ZS Series High Impedance Active Probes

- 1 GHz (ZS1000), 1.5 GHz (ZS1500) and 2.5 GHz (ZS2500) bandwidths
- High Impedance (0.9 pF, 1 M Ω)
- Extensive standard and available probe tip and ground connection accessories
- ±12 Vdc offset (ZS1500)
- Teledyne LeCroy ProBus system



High-Voltage Differential Probes

- 20 MHz and 100 MHz bandwidth
- 1,000 V_{ms} common mode voltage
- 1,400 V_{peak} differential voltage
- EN 61010 CAT III
- 80 dB CMRR at 50/60 Hz
- Teledyne LeCroy ProBus system

High-Voltage Passive Probes

- Suitable for safe, accurate high-voltage measurements
- Fixed-attenuation probes covering a range from 1 kV to 6 kV and varying transient overvoltage ratings



• Works with any 1 M Ω input oscilloscope

Current Probes

- Range of probes from 30 A_{ms} (50 A_{peak}) to 500 A_{ms} (700 A_{peak})
- 2 MHz to 100 MHz bandwidths
- Small form factor accommodates large conductors with small jaw size
- Teledyne LeCroy ProBus system



ZD Series Differential Probes

- 200 MHz, 500 MHz, 1 GHz and 1.5 GHz bandwidths
- Wide range of probing accessories
- Teledyne LeCroy ProBus system



Optical-to-Electrical Converters

- OE6250G-M 36GHz converter for NRZ and PAM4 signals up to 28 Gbaud and beyond
- OE695G 9.5 GHz converter for signals up to 12.5 Gb/s
- Fully calibrated and integrated into the oscilloscope software
- Broad wavelength range
- Low noise







2 GS/s Mixed Signal Oscilloscope Options (MS-250/MS-500)

The Mixed Signal options allow the WaveMaster 8 Zi-B to operate as a mixed signal oscilloscope with up to 36 digital channels with 2 GS/s digital sample rate and 50 Mpts/Ch.

Vertical System	WaveMaster 804Zi-B (SDA)	WaveMaster 806Zi-B (SDA/DDA)	WaveMaster 808Zi-B (SDA/DDA)	WaveMaster 813Zi-B (SDA)
Analog Bandwidth	4 GHz	6 GHz	8 GHz	13 GHz
@ 50 Ω (-3 dB)	(≥ 10 mV/div)	(≥ 10 mV/div)	(≥ 10 mV/div)	(≥ 10 mV/div)
(ProLink Input)				
Analog Bandwidth	3.5 GHz	3.5 GHz	3.5 GHz	3.5 GHz
@ 50 Ω (-3 dB) (ProBus Input)	(≥ 10 mV/div)	(≥ 10 mV/div)	(≥ 10 mV/div)	(≥ 10 mV/div)
Analog Bandwidth @ 1 MΩ (-3 dB) (ProBus Input)	500 MHz (typical, ≥ 2 mV/div)			
Rise Time	95 ps	63 ps	49 ps	32.5 ps
(10-90%, 50 Ω)	(test limit,	(test limit,	(test limit,	(test limit,
	flatness mode)	flatness mode)	flatness mode)	flatness mode)
Rise Time	71 ps	47 ps	37 ps	24.5 ps
(20-80%, 50 Ω)	(flatness mode)	(flatness mode)	(flatness mode)	(flatness mode)
Input Channels	4 (Any combination of ProLink	and ProBus inputs)		
Bandwidth Limiters	20 MHz, 200 MHz,	20 MHz, 200 MHz,	20 MHz, 200 MHz,	20 MHz, 200 MHz,
	1 GHz	1 GHz, 4 GHz	1 GHz, 4 GHz,	1 GHz, 4 GHz,
			6 GHz	6 GHz, 8 GHz
Input Impedance	ProLink Inputs: $50 \Omega \pm 2\%$ for \leq	100 mV/div, 50 Ω ±3% for > 100) mV/div	
	ProBus Inputs: $50 \Omega \pm 2\%$ or 1 l	M Ω 16 pF, 1 M Ω 11 pF with s	upplied Probe	
Input Coupling	ProLink Inputs: 50 Ω : DC, GND			
	ProBus Inputs: 1 M Ω : AC, DC, 0	SND; 50 Ω : DC, GND		
Maximum Input Voltage	50 Ω (ProLink) : ±2 V max. @ ≤	100 mV/div, 5.5 V _{rms} @ > 100 m	nV/div	
	50 Ω (ProBus): ±5 V max., 3.5 \			
	1 MΩ (ProBus): 250 V max. (pe	eak AC: < 10 kHz + DC)		
Channel-Channel	DC to 10 GHz: 50 dB (> 315:1)			
Isolation	10 to 15 GHz: 46 dB (> 200:1)			
	15 to 20 GHz : 40 dB (> 100:1)	anala aana ar different wish	ttings typical)	
	(For any two ProLink input chai	nnels, same or different v/div se	tungs, typicai)	
	015	(5250)		
Vertical Resolution	8 bits up to 11 bits with enhance	cea resolution (ERES)		

Vertical System	WaveMaster 816Zi-B (SDA)	WaveMaster 820Zi-B (SDA, DDA)	WaveMaster 825Zi-B (SDA)	WaveMaster 830Zi-B (SDA)
Analog Bandwidth @ 50 Ω (-3 dB) (2.92 mm input)			25 GHz	30 GHz
Analog Bandwidth @ 50 Ω (-3 dB) (ProLink Input)	16 GHz (≥ 10 mV/div)	20 GHz (≥ 10 mV/div)	20 GHz (≥ 10 mV/div)	20 GHz (≥ 10 mV/div)
Analog Bandwidth @ 50 Ω (-3 dB) (ProBus Input)	3.5 GHz (≥ 10 mV/div)	3.5 GHz (≥ 10 mV/div)	3.5 GHz (≥ 10 mV/div)	3.5 GHz (≥ 10 mV/div)
Analog Bandwidth @ 1 MΩ (-3 dB) (ProBus Input)	500 MHz (typical, ≥ 2 mV/div)			
Rise Time (10–90%, 50 Ω)	28.5 ps (test limit, flatness mode)	22 ps (test limit, flatness mode)	17.5 ps (test limit, flatness mode)	15.5 ps (test limit, flatness mode)
Rise Time (20–80%, 50 Ω)	21.5 ps (flatness mode)	16.5 ps (flatness mode)	13 ps (flatness mode)	11.5 ps (flatness mode)
Input Channels	4 (Any combination of Pr	oLink and ProBus inputs)	4 (Any combina ProLink inputs or 3.5 3 (1 @ full BW, 2 with ProLink o	
Bandwidth Limiters	40 GS/s mode: 20 MHz, 200 MHz, 1 GHz, 4 GHz, 6 GHz, 8 GHz, 13 GHz 80 GS/s Mode: 13 GHz	40 GS/s mode: 20 MHz, 200 MHz, 1 GHz, 4 GHz, 6 GHz, 8 GHz, 13 GHz, 16 GHz 80 GS/s Mode: 13 GHz, 16 GHz	For ≤ 20 GHz Mode: 20 MHz, 200 MHz, 1 GHz, 4 GHz, 6 GHz, 8 GHz, 13 GHz, 16 GHz For > 20 GHz Mode: 20 GHz	For ≤ 20 GHz Mode: 20 MHz, 200 MHz, 1 GHz, 4 GHz, 6 GHz, 8 GHz, 13 GHz, 16 GHz For > 20 GHz Mode: 20 GHz, 25 GHz
Input Impedance	$50 \Omega \pm 2\%$ for $\leq 100 \text{ mV/div}$, ProBus	k Inputs: $50 \Omega \pm 3\%$ for > 100 mV/div liputs: $\Omega \parallel 11$ pF with supplied Probe	ProBus	n Inputs: $50 \Omega \pm 3\%$ for > 79 mV/div Inputs: $50 \Omega \pm 3\%$ for > 100 mV/div
Input Coupling	50 Ω : D	k Inputs: DC, GND Inputs: ID; 50 Ω: DC, GND	2.92 mn 50 Ω: D ProLink	n Inputs: C, GND Inputs: C, GND Inputs:
Maximum Input Voltage	±2 V max. @ ≤ 100 mV/div 50 Ω (F ±5 V max 1 MΩ (F	ProLink): v, 5.5 V _{rms} @ > 100 mV/div ProBus): , 3.5 V _{rms} ProBus): AC: < 10 kHz + DC)	2.92 mn ±2 Vmax @ ≤ 100 mV/div 50 Ω (P ±2 Vmax @ ≤ 100 mV/div	n Inputs: , 5.5 V _{rms} @ > 100 mV/div roLink): , 5.5 V _{rms} @ > 100 mV/div roBus): , 3.5 V _{rms} ProBus):
Channel-Channel Isolation Vertical Resolution	10 to 15 GHz: 15 to 20 GHz: (For any two ProLink in	50 dB (> 315:1) 46 dB (> 200:1) 40 dB (> 100:1) nput channels, same or settings, typical)	DC to 10 GHz: 10 to 15 GHz: 15 to 20 GHz: 20 GHz to Max B (For any two ProLink or 2.92 different v/div s	46 dB (> 200:1) 40 dB (> 100:1) W: 30 dB (> 32:1) mm input channels, same or

Vertical System WaveMaster **WaveMaster** WaveMaster WaveMaster 808Zi-B (SDA/DDA) (cont'd) 813Zi-B (SDA) 804Zi-B (SDA) 806Zi-B (SDA/DDA) Sensitivity **50** Ω (ProLink): 2 mV-1 V/div. fully variable (2-9.9 mV/div via zoom) **50** Ω (ProBus): 2 mV-1 V/div, fully variable 1 M Ω (ProBus): 2 mV-10 V/div, fully variable DC Vertical Gain Accuracy ±1% F.S. (typical), offset at 0 V; ±1.5% F.S. (test limit), offset at 0 V (Gain Component of DC Accuracy) Vertical Noise Floor $0.75\,\mathrm{mV}_{\mathrm{rms}}$ 0.93 mV_{rms} $1.05\,\mathrm{mV}_{\mathrm{rms}}$ 1.21 mV_{rms} (50 mV/div) (typical) (typical) (typical) (typical) Offset Range 50 Ω (ProLink): ±500 mV @ 2-100 mV/div ±4 V @ > 100 mV/div-1 V/div 50 Ω (ProBus): ±750 mV @ 2-100 mV/div ±4 V @ > 100 mV/div-1 V/div 1 M Ω : ±1 V @ 2-140 mV/div ±10 V @ 142 mV-1.40 V/div ±100 V @ 1.42 V-10 V/div DC Vertical Offset Accuracy ±(1.5% of offset setting + 1.5% F.S. + 1 mV) (test limit) **Horizontal System** Timebases Internal time base common to 4 input channels 20 ps/div-128 s/div, depending on memory length Time/Division Range Real-time Mode: 20 ps/div-64 s/div; RIS Mode: 20 ps/div-10 ns/div: user selectable at ≤ 10 ns/div: Roll Mode: 100 ms/div up to 128 s/div, user selectable at ≥ 100 ms/div and ≤ 5 MS/s Clock Accuracy < 1 ppm + (aging of 0.5 ppm/yr from last calibration) Sample Clock Jitter Up to 10µs Acquired Time Range: 100 fsrms (Internal Timebase Reference) Up to 6.4ms Acquired Time Range: 150 fsrms (Internal Timebase Reference) Delta Time Noise Measurement Accuracy $\sqrt{2}$ (Sample Clock Jitter_{rms}) 2 + (clock accuracy * reading) Jitter Measurement Floor (Sample Clock Jitter_{rms})² SlewRate <450 fs_{rms} <425 fs_{rms} <325 fs_{rms} <500 fs_{rms} Jitter Between Channels (TIE, typical, measured at maximum bandwidth) Trigger and < 0.1 ps_{rms} (typical, software assisted), 2 ps_{rms} (typical, hardware) Interpolator Jitter

±9 x time/div. setting or 25 ns max. (whichever is larger), each channel

10 MHz; 50 Ω impedance, applied at the rear input

10 MHz; 50 Ω impedance, output at the rear

Channel-Channel

Reference (Input)

External Time base

Reference (Output)

Deskew Range External Time base

Vertical System (cont'd)	WaveMaster 816Zi-B (SDA)	WaveMaster 820Zi-B (SDA, DDA)	WaveMaster 825Zi-B (SDA)	WaveMaster 830Zi-B (SDA)
Sensitivity	(2-9.9 mV/c 50 Ω (ProLink) at 80 GS/s : (2-19.9 mV/ 50 Ω (ProBus): 2 mV	: 2 mV-1 V/div, fully variable div via zoom) : 2 mV-1 V/div, fully variable div via zoom) (-1 V/div, fully variable -10 V/div, fully variable	50 Ω (2.92 mm): 10 mV-500 mV/div, fully variable 50 Ω (ProLink): 2 mV-1 V/div, fully variable (2-9.9 mV/div via : 50 Ω (ProBus): 2 mV-1 V/div, fully variable 1 MΩ (ProBus) 2 mV-10 V/div, fully variable	
DC Vertical Gain Accuracy Gain Component of DC Accuracy)	±1% F.S. (typical), offset at 0 V;	±1.5% F.S. (test limit), offset at 0	V	
Vertical Noise Floor (50 mV/div)	1.28 mV _{rms} (typical)	1.44 mV _{rms} (typical)	1.88 mV _{rms} (typical)	2.12 mV _{rms} (typical)
Offset Range	±500 mV @ 2 ±4 V @ > 100 u 50 \(\Omega\) (F ±750 mV @ 2 ±4 V @ > 100 u ±1 V @ 2- ±10 V @ 142 u			P2 mm): 10-79 mV/div div-500 mV/div ProLink): 2-100 mV/div nV/div-1 V/div ProBus): 2-100 mV/div nV/div-1 V/div MΩ: 128 mV/div

Horizontal System

Timebases	Internal time base common to 4 input channels	
Time/Division Range	Real-time Mode at 80 GS/s: 20 ps/div-640 µs/div, depending on memory length Real-time Mode at other sample rates: 20 ps/div-128 s/div, depending on memory length Real-time Mode: 20 ps/div-64 s/div; RIS Mode: 20 ps/div-10 ns/div; user selectable at ≤ 10 ns/div; Roll Mode: 100 ms/div up to 128 s/div, user selectable at ≥ 100	For ≥ 25 GHz Mode: Real-time Mode: 20 ps/div-640 µs/div, depending on memory length For ≤ 20 GHz Mode: 20 ps/div-128 s/div, depending on memory length Real-time Mode: 20 ps/div-64 s/div; RIS Mode: 20 ps/div-10 ns/div, user selectable at ≤10 ns/div;
	ms/div and ≤ 5 MS/s	Roll Mode: 100 ms/div up to 128 s/div, user selectable at ≥ 100 ms/div and ≤ 5 MS/s
Clock Accuracy	< 1 ppm + (aging of 0.5 ppm/yr from last calibration)	
Sample Clock Jitter	Up to 10µs Acquired Time Range: 100 fsrms (Internal Timebase Up to 6.4ms Acquired Time Range: 150 fsrms (Internal Timebase	
Delta Time Measurement Accuracy	$\sqrt{2} * \sqrt{\frac{\text{Noise}}{\text{SlewRate}}}^2 + (\text{Sample Clock Jitter}_{rms})^2 + (6)$	clock accuracy * reading)
Jitter Measurement Floor	$\sqrt{\left(\frac{\text{Noise}}{\text{SlewRate}}\right)^2 + (\text{Sample Clock Jitter}_{rms})^2}$	
Jitter Between Channels (TIE, typical, measured at maximum bandwidth)		<250 fs _{rms}
Trigger and Interpolator Jitter	< 0.1 ps _{rms} (typical, software assisted), 2 ps _{rms} (typical, hardware	re)
Channel-Channel Deskew Range	±9 x time/div. setting or 25 ns max. (whichever is larger), each c	hannel
External Time base Reference (Input)	10 MHz; 50 Ω impedance, applied at the rear input	
External Time base Reference (Output)	10 MHz; 50 Ω impedance, output at the rear	

	M	-14	W	Maria Maria da m	M M A
Acquisition System		eMaster i-B (SDA)	WaveMaster 806Zi-B (SDA/DDA)	WaveMaster 808Zi-B (SDA/DDA)	WaveMaster 813Zi-B (SDA)
Single-Shot	40 GS/s on 4	Ch	· · · · · · · · · · · · · · · · · · ·		
Sample Rate/Ch	(80 GS/s on 2	? Ch using optional	WM8Zi-2X80GS External Interle	eaving Device)	
Random Interleaved Sampling (RIS)	200 GS/s for	repetitive signals (20 ps/div to 10 ns/div)		
Maximum Trigger Rate	1,000,000 wa	veforms/second (i	in Sequence Mode, up to 4 chan	nels)	
Intersegment Time	1 μs				
Maximum Acquisition Memory	256 Mpts/Ch				
Standard Memory	SDA models: DDA models:	32 Mpts, 5,000 se 64 Mpts, 15,000 se 128 Mpts, 15,000	egments max segments max	ith use of WM8Zi-2X80GS Externa	al Interleaving Device)
Memory Options	(Wernory and	Carriple riate carr	Max	THE THE STATE OF WINDER EXCERNA	in interieuving bevice)
	Option	Mem/Ch	Segments		
	M-64	64 Mpts	15,000		
	L-128	128 Mpts	15,000		
	VL-256	256 Mpts	15,000		
	(Memory and	Sample Rate can	be doubled in 1 or 2 Ch mode w	ith use of WM8Zi-2X80GS Externa	al Interleaving Device)
Acquisition Processin	na .				
Averaging		raging to 1 million	sweeps continuous averaging to	1 million sweeps	
Enhanced Resolution (ERES)		1 bits vertical reso		·	
Envelope (Extrema)	Envelope, floo	or, or roof for up to	1 million sweeps		
Interpolation	Linear or Sin	x/x			
Triggering System					
Modes	Normal, Auto	Single, and Stop			

(LITEO)				
Envelope (Extrema)	Envelope, floor, or roof for up to	1 million sweeps		
Interpolation	Linear or Sin x/x			
Triggering System				
Modes	Normal, Auto, Single, and Stop			
Sources	Any input channel, Aux, Aux/10,	Line, or Fast Edge. Slope and lev	vel unique to each source (excep	t line trigger)
Coupling Mode	DC, AC, HFRej, LFRej			
Pre-trigger Delay	0-100% of memory size (adjust	table in 1% increments of 100 ns	8)	
Post-trigger Delay	0–10,000 divisions in real time	mode, limited at slower time/div	settings or in roll mode	
Hold-off by Time	From 2 ns up to 20 s or from 1 t	o 99,999,999 events		
or Events				
Internal Trigger Range	±4.1 div from center			
Trigger Sensitivity	Not Applicable			
with Edge Trigger 2.92mm Inputs				
2.9211111 IIIputs				
Trigger Sensitivity	2 div @ < 3.5 GHz			
with Edge Trigger	1.5 div @ < 1.75 GHz			
(Ch 1-4) ProBus Inputs	1.0 div @ < 200 MHz			
	(for DC coupling, ≥ 10 mV/div, 5			
Trigger Sensitivity	2 div @ < 4 GHz,	2 div @ < 6 GHz	2 div @ < 8 GHz	3 div @ < 13 GHz
with Edge Trigger	1.5 div @ < 3 GHz,	1.5 div @ < 3 GHz	1.5 div @ < 3 GHz	1.5 div @ < 3 GHz
(Ch 1-4)	1.0 div @ < 200 MHz,	1.0 div @ < 200 MHz	1.0 div @ < 200 MHz	1.0 div @ < 200 MHz
ProLink Inputs	(for DC, AC, LFRej coupling,	(for DC, AC, LFRej coupling,	(for DC, AC, LFRej coupling,	(for DC, AC, LFRej coupling,
	≥ 10 mV/div, 50 Ω)	≥ 10 mV/div, 50 Ω)	≥ 10 mV/div, 50 Ω)	≥ 10 mV/div, 50 Ω)
	2 10 111 v / aiv, 00 32)	_ 10111v/ div, 00 <u>ua</u>)	_ 10111v/div, 00 ±2)	_ 10 111 v / div, 00 12)

Acquisition System	WaveMaste 816Zi-B (SD		WaveMaste 320Zi-B (SDA, I			aveMaster SZi-B (SDA))	WaveN 830Zi-E	
Single-Shot		40 GS/s on 4 (Ch				40 GS/s on 4	l Ch	
Sample Rate/Ch		80 GS/s on 2	Ch		(80 G	S/s on 2 Ch	when operat	ed in ≥ 25 G	Hz Mode)
Random Interleaved	200 GS/s for repe	etitive signals (2	0 ps/div to 10 ns	s/div)		For ≥ 25 (GHz Mode: N	lot applicabl	е
Sampling (RIS)					For <		de: 200 GS/s ps/div to 10		e signals
Maximum Trigger Rate	1,000,000 waveforms	/second (in Seq	uence Mode, up	to 4 chanr	nels)				
Intersegment Time	1 μs								
Maximum Acquisition Memory	5121	Mpts/Ch (2 Ch o	pperation)			512 M _l	pts/Ch (2 Ch	operation)	
Standard Memory	(SDA: 64 (DDA: 128 (SDA: 128	4 channels: pts, 5,000 segm Mpts, 15,000 se Mpts, 15,000 se 2 channels: Mpts, 15,000 se	egments max) egments max) egments max) egments max)			(SDA: 64 M (DDA: 128 N (SDA: 128 N	4 channels s, 5,000 segr pts, 15,000 s Apts, 15,000 2 channels Apts, 15,000	ments max segments m segments m s: segments m	nax) nax)
Memory Options	(DDA: 250	Mpts, 15,000 se	Max			`	Mpts, 15,000 Innels		innels
Memory options	Option	Mem/Ch	Segments			4 Cha		Z Cha	
	M-64	64 Mpts	15,000		Option	Mem/Ch	Max Segments	Mem/Ch	Max Segments
	L-128	128 Mpts	15,000		M-64	64 Mpts	15,000	128 Mpts	10,000
	VL-256	256 Mpts	15,000		L-128	128 Mpts	15,000	256 Mpts	15,000
	VL 200	200 Mpt3	10,000		VL-256	256 Mpts	15,000	512 Mpts	15,000

Acquisition Processing

Averaging	Summed averaging to 1 million	sweeps continuous averaging to	o 1 million sweeps
Enhanced Resolution (ERES)	From 8.5 to 11 bits vertical reso	lution	
Envelope (Extrema)	Envelope, floor, or roof for up to	1 million sweeps	
Interpolation	Linear or Sin x/x		
Triggering System			
Modes	Normal, Auto, Single, and Stop		
Sources	Any input channel, Aux, Aux/10,	Line, or Fast Edge. Slope and lev	vel unique to each source (except line trigger)
Coupling Mode	DC, AC, HFRej, LFRej		
Pre-trigger Delay	0-100% of memory size (adjus	table in 1% increments of 100 ns	3)
Post-trigger Delay	0-10,000 divisions in real time	mode, limited at slower time/div	settings or in roll mode
Hold-off by Time	From 2 ns up to 20 s or from 1 t	to 99,999,999 events	
or Events			
Internal Trigger Range	±4.1 div from center		
Trigger Sensitivity	Not Ap	plicable	3 div @ < 15 GHz
with Edge Trigger			1.5 div @ < 3 GHz
2.92mm Inputs			1.0 div @ < 200 MHz (for DC coupling, ≥ 10 mV/div, 50 Ω)
Trigger Sensitivity with	2 div @ < 3.5 GHz		
Edge Trigger	1.5 div @ < 1.75 GHz		
(Ch 1-4) ProBus Inputs	1.0 div @ < 200 MHz		
, ,	(for DC coupling,≥ 10 mV/div, 50	$\Omega(\Omega)$	
Trigger Sensitivity with	3 div @ < 13 GHz		3 div @ < 15 GHz
Edge Trigger	1.5 div @ < 3 GHz		1.5 div @ < 3 GHz
(Ch 1-4) ProLink Inputs	1.0 div @ < 200 MHz		1.0 div @< 200 MHz
	(for DC, AC,		(for DC, AC,
	LFRej coupling,		LFRej coupling,
	≥ 10 mV/div, 50 \(\Omega\)		≥ 10 mV/div, 50 Ω)

Triggering System (cont'd)	WaveMaster 804Zi-B (SDA)	WaveMaster 806Zi-B (SDA/DDA)	WaveMaster 808Zi-B (SDA/DDA)	WaveMaster 813Zi-B (SDA)
External Trigger	2 div @ < 1 GHz			
Sensitivity (Edge Trigger)	1.5 div @ < 500 MHz			
, , , , , , , , , , , , , , , , , , , ,	1.0 div @ < 200 MHz			
	(for DC, coupling)			
Max. Trigger Frequency,		num triggerable width 200 ps)		
SMART Trigger External Trigger	Aux (±0.4 V); Aux/10 (±4 V)			
Input Range	Aux (±0.4 v), Aux/10 (±4 v)			
Basic Triggers				
Edge		ope (positive, negative, or either) a		
Window	Triggers when signal exits a w	vindow defined by adjustable thres	holds	
TV-Composite Video		ectable line and field HDTV (720p, elds (1–8), Lines (up to 2000), Fra r Negative)		
SMART Triggers [™]				
State or Edge Qualified	selectable by time or events	only if a defined state or edge occu	·	
Qualified First		e, triggers repeatably on event B or at of the acquisition. Holdoff betwe		
Dropout		longer than selected time between		, evento
Pattern	Logic combination (AND NAN	D, OR, NOR) of 5 inputs (4 channel	s and external trigger input) Fach	source can be high low or
· accom				
	don't care. The High and Low i	evel can be selected independently	y. Triggers at start or end of the pa	ttern
SMART Triggers with E	J	evel can be selected independently	y. Triggers at start or end of the pa	ttem
SMART Triggers with E	Exclusion Technology			
Glitch	Exclusion Technology Triggers on positive or negative	ve glitches with widths selectable	as low as 200 ps to 20 s, or on into	ermittent faults
Glitch Width (Signal or Pattern)	Exclusion Technology Triggers on positive or negative, Triggers on positive, negative,	re glitches with widths selectable or both widths with widths selecta	as low as 200 ps to 20 s, or on into	ermittent faults
Glitch	Exclusion Technology Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 s	as low as 200 ps to 20 s, or on inte ble as low as 200 ps to 20 s, or on	ermittent faults
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout	Exclusion Technology Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 selectate (or transition edge) has co	as low as 200 ps to 20 s, or on into ble as low as 200 ps to 20 s, or on ccurred on another source.	ermittent faults
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified)	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectabl Triggers on any source if a giv Holdoff between sources is 1	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 steen state (or transition edge) has consto 20 s, or 1 to 99,999,999 ever	as low as 200 ps to 20 s, or on into ble as low as 200 ps to 20 s, or on ccurred on another source. ts	ermittent faults intermittent faults
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectabl Triggers on any source if a giv Holdoff between sources is 1 Trigger on positive or negative	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 selectate for transition edge) has consisted to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits	as low as 200 ps to 20 s, or on into ble as low as 200 ps to 20 s, or on ccurred on another source. ts and two time limits. Select betwee	ermittent faults intermittent faults en 1 ns and 20 ns
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified)	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectabl Triggers on any source if a giv Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 steen state (or transition edge) has consto 20 s, or 1 to 99,999,999 ever	as low as 200 ps to 20 s, or on inte ble as low as 200 ps to 20 s, or on ccurred on another source. ts and two time limits. Select betwee dge limits between 1 ns and 20 ns	ermittent faults intermittent faults en 1 ns and 20 ns
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Seguence) T	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable. Triggers on any source if a given Holdoff between sources is 1. Trigger on positive or negative. Trigger on edge rates. Select I Trigger on intermittent faults in triggering.	ve glitches with widths selectable and or both widths with widths selectable between 1 ns and 20 selectable sensition edge) has consisted to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits imits for dV, dt, and slope. Select expressions to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits imits for dV, dt, and slope. Select expressions are selected behaviors.	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on ccurred on another source. Its and two time limits. Select betweed dge limits between 1 ns and 20 ns or and triggering when that condit	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable. Triggers on any source if a given Holdoff between sources is 1 Trigger on positive or negative. Trigger on edge rates. Select I Trigger on intermittent faults I Triggering. Arm on "A" event, then Trigger	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 selected the state (or transition edge) has consisted to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits imits for dV, dt, and slope. Select e	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on ccurred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Triggering when the condite the property of the conditions are the conditions.	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Seguence) T	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind	ve glitches with widths selectable and or both widths with widths selectable between 1 ns and 20 selectable for transition edge) has considered by two voltage limits imits for dV, dt, and slope. Select expressions to 20 specifying the expected behavior on "B" event. Or Arm on "A" event,	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on ccurred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Triger on "D" event	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event.
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Mea	ve glitches with widths selectable and sort both widths with widths selectable between 1 ns and 20 selected services are state (or transition edge) has considered as to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits imits for dV, dt, and slope. Select expressions are selected behavior on "B" event. Or Arm on "A" event, lify on "B" then "C" event, and Trigglow, Pattern (Logic) Width, Glitch, I assurement): Edge, Window, Pattern	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event Measurement can be on
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable. Triggers on any source if a give Holdoff between sources is 1. Trigger on positive or negative. Trigger on edge rates. Select I Trigger on intermittent faults I Triggering. Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only.	ve glitches with widths selectable and sort both widths with widths selectable between 1 ns and 20 selected services are state (or transition edge) has considered as to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits imits for dV, dt, and slope. Select expressions are selected behavior on "B" event. Or Arm on "A" event, lify on "B" then "C" event, and Trigglow, Pattern (Logic) Width, Glitch, I assurement): Edge, Window, Pattern	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event Measurement can be on
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Mea	ve glitches with widths selectable and provided by the selectable selectable selectable selectable between 1 ns and 20 selectable se	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event Measurement can be on
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Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Measurement can be on Stage C of Cascade A then B then C: Edg Cascade A then B then C then Holdoff between A and B, B ar	ve glitches with widths selectable and both widths with widths selectable or both widths with widths selectable between 1 ns and 20 select sensition edge) has considered by the selectation of the selecta	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement on (Logic), Width, Glitch, Interval, Dropout, or Measurement on (1ns to 20s) or number of events.	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event. Measurement can be on opout, or Measurement. Mea an be on Stage D only.
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Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability Types Holdoff High-speed Serial Prof	Triggers on positive or negative, Triggers on positive, negative, Triggers on intervals selectable Triggers on any source if a give Holdoff between sources is 1 Trigger on positive or negative Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Measurement can be on Stage C of Cascade A then B then C: Edg Cascade A then B then C then Holdoff between A and B, B ar Measurement trigger selection prior stage and the last stage.	ve glitches with widths selectable and both widths with widths selectable or both widths with widths selectable between 1 ns and 20 sometimes are state (or transition edge) has considered by the selectation of the selectat	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between dge limits between 1 ns and 20 ns or and triggering when that condite then Qualify on "B" event, and Trigger on "D" event nterval, Dropout, or Measurement on (Logic), Width, Glitch, Interval, Dropout, or Measurement on (1ns to 20s) or number of events.	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event. Measurement can be on opout, or Measurement. Mea an be on Stage D only.
Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability Types Holdoff	Triggers on positive or negative. Triggers on positive, negative, Triggers on intervals selectabl. Triggers on any source if a giv. Holdoff between sources is 1 Trigger on positive or negative. Trigger on edge rates. Select I Trigger on edge rates. Select I Trigger on intermittent faults I Triggering Arm on "A" event, then Trigger Or Arm on "A" event, then Qual Cascade A then B: Edge, Wind Stage B only. Cascade A then B then C (Measurement can be on Stage C oc Cascade A then B then C: Edg Cascade A then B then C then Holdoff between A and B, B ar Measurement trigger selection prior stage and the last stage. tocol Triggering Option WM8Zi-6GBIT-80b-SYM	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 s ren state (or transition edge) has constant to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits imits for dV, dt, and slope. Select early specifying the expected behavior on "B" event. Or Arm on "A" event, lify on "B" then "C" event, and Trigglow, Pattern (Logic) Width, Glitch, I asurement): Edge, Window, Pattern (Logic). D: Edge, Window, Pattern (Logic). D: Edge, Window, Pattern (Logic), and C, C and D is selectable by time in as the last stage in a Cascade put MBOL-TD: 600 Mb/s to 6.5 Gb/s, Cl	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between the description of the condition of	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event. Measurement can be on opout, or Measurement. Mea an be on Stage D only.
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Glitch Width (Signal or Pattern) Interval (Signal or Pattern) Timeout (State/Edge Qualified) Runt Slew Rate Exclusion Triggering Cascade (Sequence) T Capability Types Holdoff High-speed Serial Prof	Triggers on positive or negative. Triggers on positive, negative, Triggers on intervals selectable. Triggers on any source if a give. Holdoff between sources is 1 Trigger on positive or negative. Trigger on edge rates. Select 1 Trigger on edge rates. Select 1 Trigger on intermittent faults between of the money of th	ve glitches with widths selectable or both widths with widths selectable between 1 ns and 20 s ren state (or transition edge) has constant to 20 s, or 1 to 99,999,999 ever runts defined by two voltage limits imits for dV, dt, and slope. Select early specifying the expected behavior on "B" event. Or Arm on "A" event, lify on "B" then "C" event, and Trigglow, Pattern (Logic) Width, Glitch, I asurement): Edge, Window, Pattern (Logic). D: Edge, Window, Pattern (Logic). D: Edge, Window, Pattern (Logic), and C, C and D is selectable by time in as the last stage in a Cascade put MBOL-TD: 600 Mb/s to 6.5 Gb/s, Cl	as low as 200 ps to 20 s, or on interble as low as 200 ps to 20 s, or on courred on another source. Its and two time limits. Select between the description of the d	ermittent faults intermittent faults en 1 ns and 20 ns s ion is not met ger on "C" event. Measurement can be on opout, or Measurement. Mea- an be on Stage D only.

Pattern Length	80 bits NRZ, eight 8b/10b symbols, 64b/66b symbol
Clock and Data Outputs	No Clock and Data Recovery outputs provided

Low Speed Serial Protocol Triggering (Optional)

I²C, SPI (SPI, SSPI, SIOP), UART-RS232, CAN, LIN, FlexRay, MIL-STD-1553, AudioBus

Measurement Trigger

SMART Trigger External Trigger External Trigger External Trigger Edge Basic Triggers Edge Window Triggers wh Triggers wh Triggers wh Triggers wh (50 or 60 Hz (1:1, 2:1, 4:1) SMART Triggers™ State or Edge Qualified Triggers on lectable by Qualified First In Sequence is satisfied Dropout Triggers if s Pattern Logic comb care. The H SMART Triggers with Exclusion T Glitch Triggers on Interval (Signal or Pattern) Triggers on Interval (Signal or Pattern) Triggers on (State/Edge Qualified) Runt Trigger on interval (Signal or Pattern) Slew Rate Exclusion Triggering Cascade (Sequence) Triggering Cascade (Sequence) Triggering Cascade A Stage B on Cascade A Stage B on Cascade A Surement of Cascade A Cascade A Holdoff Holdoff bet Measurement	500 MHz 200 MHz 2upling) ≥ 10 mV/div (minin /); Aux/10 (±4 V) men signal meets slopen signal exits a w FSC or PAL with select 2) and Line or CUST(1, 8:1), or Synch Pul many input source of time or events are acquisition mode in the first segment signal drops out for bination (AND, NANE)		nolds 1080i, 1080p) with selectable fra es (up to 2000), Frame Rates (25, 3 rred on another input source. Hol ly if a defined pattern, state, or ec	30, 50, or 60 Hz), Interlacing		
1.0 div @ <	200 MHz upling) ≥ 10 mV/div (minin r); Aux/10 (±4 V) men signal meets slanen signal exits a w FSC or PAL with sela z) and Line or CUSTO 1, 8:1), or Synch Pul an any input source of time or events be acquisition mode in the first segment signal drops out for bination (AND, NANE	ope (positive, negative, or either) and indow defined by adjustable threst ectable line and field HDTV (720p, OM with selectable Fields (1–8), Line lise Slope (Positive or Negative) only if a defined state or edge occurs, triggers repeatably on event B on at of the acquisition. Holdoff between longer than selected time between	nolds 1080i, 1080p) with selectable fra es (up to 2000), Frame Rates (25, 3 rred on another input source. Hol ly if a defined pattern, state, or ec	30, 50, or 60 Hz), Interlacing		
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is satisfied Dropout Triggers if s Pattern Logic comb care. The H SMART Triggers with Exclusion T Glitch Triggers on Width (Signal or Pattern) Triggers on Interval (Signal or Pattern) Triggers on (State/Edge Qualified) Holdoff bet Runt Trigger on p Slew Rate Trigger on or Exclusion Triggering Cascade (Sequence) Triggering Types Cascade A Stage B on Cascade A Stage B on Cascade A Stage B on Cascade A Surement or Cascade A Holdoff Holdoff bet Measuremen prior stage	in the first segment signal drops out for bination (AND, NAND	t of the acquisition. Holdoff between longer than selected time between				
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Interval (Signal or Pattern) Triggers on Timeout Triggers on Runt Trigger on p Slew Rate Trigger on or Exclusion Triggering Trigger on or Exclusion Triggering Trigger on or Trigger on		e glitches with widths selectable as				
Timeout (State/Edge Qualified) Holdoff bet Runt Trigger on public Slew Rate Trigger on its Exclusion Triggering Exclusion Trigger on its Exclusion Trig	positive, negative, or	r both widths with widths selectable a	as low as 200 ps to 20 s, or on inte	rmittent faults		
(State/Edge Qualified) Runt Trigger on p Slew Rate Trigger on p Exclusion Triggering Trigger on p Cascade (Sequence) Triggering Capability Arm on "A" event, then Types Cascade A Stage B on Cascade A surement of Cascade A Holdoff Holdoff Holdoff bet Measuremen prior stage		e between 1 ns and 20 s				
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event, then Types Cascade A Stage B onl Cascade A surement o Cascade A Cascade A Holdoff Holdoff Holdoff bet Measureme prior stage	event then Trigger	on "B" event. Or Arm on "A" event, t	hen Qualify on "B" event, and Tric	gger on "C" event Or Arm on "i		
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Stage B onl Cascade A surement of Cascade A Cascade A Holdoff Holdoff Holdoff Measurement of prior stage	thon P: Edgo Wind	ow, Pattern (Logic) Width, Glitch, In	storyal Drangut or Maggurament	t Massurament can be on		
Cascade A surement of Cascade A Cascade A Holdoff Holdoff Measurement prior stage		ow, rattern (Logic) Width, Gilton, in	iterval, bropout, or incasurement	Wedsdreffield dail be off		
surement of Cascade A Cascade A Holdoff Holdoff Measurement of the control of the	Cascade A then B then C (Measurement): Edge, Window, Pattern (Logic), Width, Glitch, Interval, Dropout, or Measurement. Mea					
Cascade A Cascade A Holdoff Holdoff Measureme prior stage	surement can be on Stage C only.					
Cascade A Holdoff Holdoff Measureme prior stage	Cascade A then B then C: Edge, Window, Pattern (Logic).					
Holdoff Holdoff bet Measureme prior stage	9	D: Edge, Window, Pattern (Logic), o	or Measurement, Measurement o	can be on Stage D only		
Measureme prior stage	ween A and B B ar	nd C, C and D is selectable by time (Ins to 20s) or number of events	i		
prior stage		n as the last stage in a Cascade pre				
· -	and the last stage.					
High-speed Serial Protocol Trigge						
	ering					
Data Rates	Option WM8Zi-6G	BIT-80b-SYMBOL-TD: /s, Channel 4 input only	Option WM8Zi-6GBl 600 Mb/s to 6.5 Gb/s,			
		GBIT-80b-SYMBOL-TD:	Option WM8Zi-14GBI	· · · · · · · · · · · · · · · · · · ·		
6	· ·	o/s, Channel 4 input only	600 Mb/s to 14.1 Gb/s			
(Note:	Channel 3 input will	Il capture signal for triggering e is in ≥25 GHz mode)	(Note: Channel 3 input will c when oscilloscope is			
		on SDA models:	(Standard on S	SDA models:		
	when oscilloscope (Standard o		600 Mb/s to 6.5 Gb/s,			
60	when oscilloscope (Standard o 600 Mb/s to 6.5 Gb/	ACDIT OOK OVAROU TO	Option SDA8Zi-UPG-140 600 Mb/s to 14.1 Gb/s,			
Pattern Length 80 bits NR2	when oscilloscope (Standard o 500 Mb/s to 6.5 Gb/ otion SDA8Zi-UPG-1 00 Mb/s to 14.1 Gb/	/s, Channel 4 input only)				

Low Speed Serial Protocol Triggering (Optional)

I²C, SPI (SPI, SSPI, SIOP), UART-RS232, CAN, LIN, FlexRay, MIL-STD-1553, AudioBus

Measurement Trigger

Color Waveform Display	WaveMaster 804Zi-B (SDA)	WaveMaster 806Zi-B (SDA/DDA)	WaveMaster808Zi-B (SDA/DDA)	WaveMaster 813Zi-B (SDA)
Гуре	Color 15.3" flat panel TFT-Activ	ve Matrix LCD with high resolution	n touch screen	
Resolution	WXGA; 1280 x 768 pixels			
Number of Traces	Display a maximum of 16 trac math traces.	es (up to 40 with some software	options). Simultaneously display c	hannel, zoom, memory and
Grid Styles	Auto, Single, Dual, Triple, Quad Up to twenty grids available w	, Octal, X-Y, Single+X-Y, Dual+X-Y, ith some software options	Twelve, Sixteen.	
Waveform Representation	Sample dots joined, or sample			
ntegrated Second Dis	enlav			
ntegrated occord bis	<u> </u>	tion of user-supplied second dis	play with split-grid capability.	
		second display may not be a Fuji		
Processor/CPU				
Гуре	Intel® CoreTM i7-4770S Quad	, 3.1 GHz (up to 3.9 GHz in Turbo	mode) (or better)	
Processor Memory		y (32 Mpt), and M-64 memory or		
Operating System	Microsoft Windows® 7 Profess	sional Edition (64-bit)		
Real Time Clock			NTP support to synchronize to pred	cision internal clocks
nterface				
Remote Control	Via Windows Automation, or v	ia Teledyne LeCroy Remote Com	mand Set	
Network Communication Standard	VXI-11 or VICP, LXI Class C (v1			
GPIB Port (Optional)	Supports IEEE - 488.2			
SIB Port (Optional)	Supports PCIe Gen1 x4 protoc	ol with Teledyne LeCroy supplied	API	
Ethernet Port	Supports 10/100/1000BaseT			
JSB Ports		2.0 ports (front panel) support W		
External Monitor Port	Full-size DisplayPort connecto	r to support customer-supplied of	external monitor.	
	Includes support for extended	desktop operation with second i	monitor.	
Serial Port	Not Available			
Power Requirements Voltage	100-240 VAC ±10% at 45-66	Hz, 100-120 VAC ±10% at 380-	-420 Hz, Automatic AC Voltage Sele	ection, Installation Categor
Max. Power Consumption	975 W / 975 VA		<u> </u>	<u> </u>
Environmental				
Temperature (Operating)	+5 °C to +40 °C			
Temperature	-20 °C to +60 °C			
(Non-Operating)	20 0 10 100 0			
Humidity	5% to 80% relative humidity (n	on-condensing) up to +31 °C.		
Operating)		ative humidity (non-condensing)	at +40 °C	
Humidity		on-condensing) as tested per MI		
Non-Operating)	, ,	3/		
Altitude	Up to 10,000 ft. (3048 m) at or	below +25 °C		
Operating) Random Vibration	0.5 a _{rms} 5 Hz to 500 Hz 15 mi	nutes in each of three orthogona	laxes	
Operating)				
Random Vibration (Non-Operating)	2.4 g _{rms} 5 Hz to 500 Hz, 15 mi	nutes in each of three orthogona	l axes	
Functional Shock	20 g _{peak} , half sine, 11 ms pulse,	3 shocks (positive and negative)	in each of three orthogonal axes, 18	shocks total
Physical Dimensions				
Dimensions (HWD)		467 x 406 mm) height excludes f	eet	
Weight	51.5 lbs. (23.4 kg)	, J		
Shipping Weight	70 lbs. (31.8 kg)			
Certifications				
J. HIIVANOIIO	CE Compliant, UL and cUL listed CSA C22.2 No. 61010-1-12	d; conforms to EN 61326, EN 6101	0-1, EN61010-2-030, UL 61010-1 3rd	d edition, and
Warranty and Service				
with out the	3-year warranty calibration rec	commended annually.		
		lude extended warranty, upgrade	s, and calibration services	
	. •	, . ,		

Fige Color 18.3° flat pond FTF-Active Natrix (CO with high resolution butch screen WXX64, 1926 768 push Number of Traces Display or reakman of 16 traces (up to 49 with some software options). Simultaneously display channel, zoom, memory and month traces. Grid Styles Auto. Single, Dual, Taple, Quad, Ortal, X-Y, Singler-K-Y, Dual-X-Y, Twelve, Suteen Use to twenty ords evalible with some software options. Waveform Representation Sample dolds jorted, or sample dolds only Number of Display Integrated Second Display Supports studin screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with splinged capability (Note touch screen integration of user-supplied second display with screen integration of users scr	Color Waveform Display	WaveMaster 816Zi-B (SDA)	WaveMaster 820Zi-B (SDA, DDA)	WaveMaster 825Zi-B (SDA)	WaveMaster 830Zi-B (SDA)
Number of Traces Display a maximum of 16 traces up to 40 with some software options. Brid Styles Auto, Single, Dual, Triple, Quad, Octal, X*Y Single-XY, Dual-XY, Twelve, Sindeen. Up to twenty gine available with some software options. Western Representation Sample dots joined, or sample dots only Integrated Second Display Supports touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration of user-supplied second display with spir-grid capability. Processor/CPU Type. Processor/CPU Type. Interded Screen integration of user-supplied second display with spir-grid capability. (Note: touch screen integration (St Mit) to 3 9 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0		Color 15.3" flat panel TFT-Acti			•
math traces. Auto, Single, Dual, Triple, Quad, Octal, XY, Single-XY, Dual+XY, Twelve, Sixteen. Dual traces and the second octal oct	Resolution				
Weekform Representation Sample date joined, or sample date with some software options. Weekform Representation Sample date joined, or sample date on the sample date of the sample date	Number of Traces		ees (up to 40 with some software op	otions). Simultaneously display	channel, zoom, memory and
Augusted Second Display Supports touch screen integration of user-supplied second display with spit-grid capability. (Note: touch screen driver for second display may not be a Fujitau driver) Processor/CPU Viscosor/CPU Viscos	Grid Styles		•	welve, Sixteen.	
Supports touch screen integration of user-supplied second display with spit-grid capability. (Note touch screen driver for second display may not be a Fujitsu driver) Processor/CPU Type Intel® CoreTM 17-4770S Quad. 3.1 GHz (up to 3.9 GHz in Turbo mode) (or better) Tocessor Memory 8 6 B standard for 1770 memory (32 Mgy), and Mc42 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard for 1-128 and VI. 256 memory options 16 GB standard with the spit of t	Waveform Representation				
Supports touch screen integration of user-supplied second display with split-grid capability. [Note: touch screen driver for second display may not be a Fujitsu driver) Processor/CPU Type Intel® CoreTM (7-4770S Quad. 3.1 GHz (up to 3.9 GHz in Turbo mode) (or better) Forecessor Memory 8 6 B standard for 1770 memory (32 Mpt), and M-64 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard for 1-128 and V1-256 memory options 16 GB standard v2-128 memory options 17 GB standard v2-128 memory options 18 memory options	Integrated Second Dis	nlav			
Processor/CPU Type Intel® CoreTM I7 4770S Quad, 8.1 GHz (up to 2.9 GHz in Turbo mode) (or better) 8 GB standard for STD memory (32 Mpt), and M-64 memory options 16 GB standard for L128 and VL 256 memory options 16 GB standard for L128 and VL 256 memory options 16 GB standard for L128 and VL 256 memory options 19 to 32 GB optional Determine Control Via Windows Automation, or via Teledyne LeCroy Remote Command Set Verwork Communication VX+11 or ViCP, LX Class G (v.1.2) Compliant Standard Supports IEEE – 488.2 SIB Pott (Optional) Supports Individe SIB Pott Sib Potter (Optional) Supports IEEE – 488.2 SIB Pott (Optiona	integrated Second Dis	Supports touch screen integra			
Processor Memory B GB standard for 1719 and VI-26 memory options 16 GB standard for 1719 and VI-26 memory options 16 GB standard for 1719 and VI-26 memory options 16 GB standard for 1719 and VI-26 memory options 17 GB standard for 1719 and VI-26 memory options 18 GB standard for 1719 and VI-26 memory options 19 GB optional 20 perating System Microsoft Windows* 7 Professional Edition (64-bit) 19 Determined System Microsoft Windows* 7 Professional Edition (64-bit) 10 Determined System Microsoft Windows* 7 Professional Edition (64-bit) 10 Determined System Microsoft Windows Automation, or via Teledyne LeCroy Remote Command Set Network Communication VI-11 or VICPLXI Class C (VI.2) Compliant 18 Determined Standard 18 Determined Supports IEEE – 488.2 18 BPOT (Optional) 18 Determined Supports IEEE – 488.2 18 BPOT (Optional) 18 Supports IEEE – 488.2 18 BPOT (Optional) 19 Supports IEEE – 488.2 19 Supports IEEE –	Processor/CPU	(,	
16 GB standard for L-128 and VL-256 memory options	Туре	Intel® CoreTM i7-4770S Quad	l, 3.1 GHz (up to 3.9 GHz in Turbo m	node) (or better)	
Deersting System Microsoft Windows* 7 Professional Edition (64 bit) Remail Time Clock Date and time displayed with waveform an in hardcopy files. SNTP support to synchronize to precision internal clocks Interface Network Communication Via Windows Automation, or via Teledyne LeCroy Remote Command Set Network Communication VXI-11 or VICP, LXI Class C (V1.2) Compliant Standard Standard Standard Supports EEE 488.2 Supports EEE 488.2 Supports EEE 488.2 Supports Port (Optional) Supports PCIG earl V4 protocol with Teledyne LeCroy supplied API Subports Port Supports PCIG earl V4 protocol with Teledyne LeCroy supplied API Subports Pull-size Displayer of connector to support clustomer supplied external monitor Includes support for extended desktop operation with second monitor. Serial Port Not Available Peripheral Bus Teledyne LeCroy LBUS standard Power Requirements Voltage 100-240 VAC ±10% at 45-66 Hz, 100-120 VAC ±10% at 380-420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption 975 W / 975 VA 1025 W / 1025 VA Privionmental Peripheral U2 Power Priving Peripheral U3 Power Priving Priving Power Priving P	Processor Memory	16 GB standard for L-128 and		ons	
### Page 12 Page 13 Page 14 Pa	Operating System		sional Edition (64-bit)		
Remote Control Via Windows Automation, or via Teledyne LeCroy Remote Command Set Network Communication VXH-11 or VICP, LXI Class C (V.12) Compliant Standard SPIB Port (Optional) Supports IEEE – 488.2 SIB Port (Optional) Supports DCIe Gen1 x4 protocol with Teledyne LeCroy supplied API Sibrory Automatic Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SIB Port Supports 10/100/1000Base F tehernet interface (R.M.5 port) SI		Date and time displayed with w	aveform an in hardcopy files. SNTP s	support to synchronize to precision	on internal clocks
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Supports PCIe Gent xd protocol with Teledyne LeCroy supplied API	Network Communication				
Ethernet Port Supports 10/100/100/BaseT Ethernet interface (R.J.45 port) JSB Ports 4 USB 3.0 ports (rear), 3 USB 2.0 ports (front panel) support Windows compatible devices External Monitor Port Includes support to extended desktop operation with second monitor. Includes support for extended desktop operation with second monitor. Peripheral Bus Teledyne LeCroy LBUS standard Power Requirements Voltage 100–240 VAC ±10% at 45–66 Hz, 100–120 VAC ±10% at 380–420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption 975 W / 975 VA 1025 W / 1025 W					
JUSB 20 ports (rear), 3 USB 2.0 ports (front panel) support Windows compatible devices Seternal Monitor Port Full-size DisplayPort connector to support customer-supplied external monitor. Includes support for extended desktop operation with second monitor. Not Available Peripheral Bus Teledyne LeCroy LBUS standard Power Requirements Voltage 100–240 VAC ±10% at 45–66 Hz, 100–120 VAC ±10% at 380–420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption 975 W / 975 VA 1025 W / 1025 W A 1025 W / 1025 W A Environmental Femperature +5 °C to +40 °C Operating) - 20 °C to +60 °C Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) up to +31 °C. Upperating) - Upper limit derates to 50% relative humidity (non-condensing) at +40 °C - Humidity 5% to 95% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) - Upper limit derates to 50% relative humidity (non-condensing) as tested per				PI	
External Monitor Port Includes support for extended desktop operation with second monitor. Includes support for extended desktop operation with second monitor. Serial Port Not Available Teledyne LeCroy LBUS standard Power Requirements Voltage 100–240 VAC ±10% at 45–66 Hz, 100–120 VAC ±10% at 380–420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption 975 W / 975 VA 1025 W / 1025 VA Included 1025 W / 1025 W / 1025 VA Included 1025 W / 1025 W / 1025 VA Included 1025 W / 1025 W / 1025 W / 1025 W /					
Includes support for extended desktop operation with second monitor. Serial Port Not Available Peripheral Bus Teledyne LeCroy LBUS standard Power Requirements Voltage 100-240 VAC ±10% at 45-66 Hz, 100-120 VAC ±10% at 380-420 Hz, Automatic AC Voltage Selection, Installation Category Max Power Consumption 975 W / 975 VA 1025 W / 1025 VA Invironmental Temperature 45 °C to +40 °C Operating) Humidity 5% to 80% relative humidity (non-condensing) up to +31 °C. Upper limit derates to 50% relative humidity (non-condensing) at +40 °C Upperating) Humidity 5% to 95% relative humidity (non-condensing) as tested per MIL-PRF-28800F Non-Operating) Non-Operating) Non-Operating) Non-Operating) Altitude Up to 10,000 ft. (3048 m) at or below +25 °C Operating) Random Vibration Operating) Non-Operating) Non-Operating) Power Requirements 2.4 g _{ms} 5 Hz to 500 Hz, 15 minutes in each of three orthogonal axes Operating) Non-Operating) Non-Operating) Power Requirements 14* H x 18.4* W x 16* D (355 x 467 x 406 mm) height excludes feet Neight 10* Standard Vibration Non-Operating) 14* H x 18.4* W x 16* D (355 x 467 x 406 mm) height excludes feet Neight 10* Standard Vibration Non-Operating) CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12					
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Power Requirements Voltage 100–240 VAC ±10% at 45–66 Hz, 100–120 VAC ±10% at 380–420 Hz, Automatic AC Voltage Selection, Installation Category Max. Power Consumption 975 W / 975 VA 1025 W / 1025 W / 1025 W / Environmental Temperature					
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Environmental Temperature					
Temperature	Max. Power Consumption	975 W	/ / 975 VA	1025 W /	′ 1025 VA
Coperating Cop		+5 °C to +10 °C			
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Physical Dimension Dimensions (HWD) 14" H x 18.4" W x 16" D (355 x 467 x 406 mm) height excludes feet Weight 51.5 lbs. (23.4 kg) 58 lbs. (26.4 kg) Shipping Weight 70 lbs. (31.8 kg) 76.0 lbs. (34.5 kg) Certifications CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12		00 1. 15 1. 22	O alterative for a 191 and 191	and the state of t	0 -111
Dimensions (HWD) 14" H x 18.4" W x 16" D (355 x 467 x 406 mm) height excludes feet Weight 51.5 lbs. (23.4 kg) Shipping Weight 70 lbs. (31.8 kg) 76.0 lbs. (34.5 kg) Certifications CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12	Functional Shock	20 g _{peak} , half sine, 11 ms pulse	, 3 shocks (positive and negative) in (each of three orthogonal axes, 1	8 shocks total
Weight 51.5 lbs. (23.4 kg) 58 lbs. (26.4 kg) Shipping Weight 70 lbs. (31.8 kg) 76.0 lbs. (34.5 kg) Certifications CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12		14"11 v 10 4" \\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	467 v 406 pops) hainhall. 5		
Shipping Weight 70 lbs. (31.8 kg) 76.0 lbs. (34.5 kg) Certifications CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12					(26.41m)
CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12			, ,,		
CE Compliant, UL and cUL listed; conforms to EN 61326, EN 61010-1, EN61010-2-030, UL 61010-1 3rd edition, and CSA C22.2 No. 61010-1-12	Snipping Weight	/0 lbs	. (उ1.8 Kg)	/6.0 lbs.	(34.5 Kg)
CSA C22.2 No. 61010-1-12	Certifications				
Narranty and Service			d; conforms to EN 61326, EN 61010-	1, EN61010-2-030, UL 61010-1 3	rd edition, and
	Warranty and Service				

Standard

Math Tools

Display up to 8 math function traces (F1 - F8). The easy-to-use graphical interface simplifies setup of up to two operations on each function trace, and function traces can be chained together to perform math-on-math.

absolute value integral

average (summed) interpolate (cubic, quadratic, sinx/x)

average (continuous) invert (negate)
correlation log (base e)
(two waveforms) log (base 10)
derivative product (x)
deskew (resample) ratio (/)
difference (-) reciprocal
enhanced resolution rescale (with unit

ennanced resolution
(to 11-bits vertical)
envelope
exp (base e)
exp (base 10)
fft (power spectrum, magnitude, phase, up to max Mpts)
floor
rescale (with units)
roof
sparse
square
square root
sum (+)
zoom (identity)

Measure Tools

Display any 12 parameters together with statistics, including their average, high, low, and standard deviations. Histicons provide a fast, dynamic view of parameters and wave shape characteristics. Parameter Math allows addition, subtraction, multiplication, or division of two different parameters.

amplitude level @ x maximum std. deviation area mean base top width median cycles minimum phase data time @ minimum (min.) delay narrow band phase

Δ delay narrow band power time @ maximum (max.) number of points Δ time @ level duty cycle duration + overshoot Δ time @ level from trigger falltime (90-10%, - overshoot 80-20%, @ level) x @ max. peak-to-peak frequency x @ min. period

first risetime (10–90%, last 20–80%, @ level)

Pass/Fail Testing

Simultaneously test multiple parameters against selectable parameter limits or pre-defined masks. Pass or fail conditions can initiate actions including document to local or networked files, e-mail the image of the failure, save waveforms, send a pulse out at the front panel auxiliary BNC output, or (with the GPIB option) send a GPIB SRQ.

Basic Jitter and Timing Analysis Tools

This package provides toolsets for displaying parameter values vs. time, statistical views of parameters using histograms, and persistence view math functions. These tools include:

· "Track" graphs of all parameters, no limitation of number

Cycle-Cycle Jitter
 N-Cycle
 N-Cycle with
 N-Cycle with
 Setup
 Half Period
 Hold
 N-Cycle with
 Start selection
 Time Interval

- Time Interval - Duty Cycle @ level - Duty Cycle Error @ level - Duty Cycle Error

- · Histograms expanded with 19 histogram parameters and up to 2 billion events
- Trend (datalog) of up to 1 million events
- Track graphs of all parameters
- Persistence histogram, persistence (range, sigma)

Standard (cont'd)

Advanced Customization

Provides capability to create a math function or measurement parameter in MATLAB, Excel, C++, JavaScript, or Visual Basic Script (VBS) format and insert it into the oscilloscope's processing stream. All results are processed and displayed on the oscilloscope grid, and are available for further processing. Also permits the creation of customized plug-ins that can be inserted into the scope user interface, control of the scope via Visual Basic scripts embedded in customized functions, and use of Teledyne LeCroy's Custom DSO capabilities.

Software Options

SDAIII Serial Data Analysis Software (WM8Zi-SDAIII) (Included in WM8Zi-SDAIII option, Standard on SDA 8 Zi-B and DDA 8 Zi-B Models)

Total Jitter

A complete jitter measurement and analysis toolset with the SDAIII-CompleteLinQ user interface framework. The CompleteLinQ framework provides a single user interface for "LinQ", "Crosstalk", "EyeDrII" and "Virtual Probe" capabilities (purchased separately).

SDAIII provides complete serial data and clock jitter and eye diagram measurement and analysis capabilities. Eye Diagrams with millions of UI are quickly calculated from up to 512 Mpt records, and advanced tools may be used on the Eye Diagram to aid analysis. Complete TIE and Total Jitter (Tj) parameters and analysis functions are provided. Comparison of eye diagrams and jitter analysis between captured lanes and one "reference" location is provided. Includes:

- Time Interval Error (TIE) Measurement Parameter, Histogram, Spectrum and Jitter Track
- Total Jitter (Tj) Measurement Parameter, Histogram
- Spectrum
- · Eye Diagram Display (sliced)
- Eye Diagram IsoBER (lines of constant Bit Error Rate)
- Eye Diagram Mask Violation Locator
- · Eye Diagram Measurement Parameters

Eye Height
One Level
Zero Level
Eye Crossing
Avg. Power
Bit Error Rate
Eye Amplitude
Extinction Ratio
Slice Width (setting)

- Q-Fit Tail Representation
- Bathtub Curve
- Cumulative Distribution Function (CDF)
- PLL Track

Jitter Decomposition Models

Three dual-dirac jitter decomposition methods are provided for maximum measurement flexibility. Q-Scale, CDF, Bathtub Curve, and all jitter decomposition measurement parameters can be displayed using any of the three methods.

- · Spectral, Rj Direct
- Spectral, Rj+Dj CDF Fit
- · NQ-Scale

Random Jitter (Rj) and Non-Data Dependent Jitter (Rj+BUj) Analysis

Random Jitter (Rj) Meas Param
 Periodic Jitter (Pj) Meas Param
 Rj+BUj Spectrum
 Rj+BUj Track
 Rj+BUj Histogram
 Pj Inverse FFT

Deterministic Jitter (Dj) Analysis

· Deterministic Jitter (Dj) Measurement Parameter

Software Options (cont'd)

SDAIII Serial Data Analysis Software (continued)

Data Dependent Jitter (DDj) Analysis

- · Data Dependent Jitter (DDj) Param
- Duty Cycle Distortion (DCD) Param
- · InterSymbol Interference (ISI) Param
- DDj Plot (by Pattern or N-bit Sequence)
- DDj Histogram
- · ISI Plot (by Pattern)

· Digital Pattern display

Reference Lane

 Compare current acquisition to Reference with a side-by-side or single (tabbed) display mode

SDAIII "LinQ" Capability

(SDAIII-LinQ, SDAIII-CrossLinQ, and SDAIII-CompleteLinQ Options)

In addition to all SDAIII capabilities, "LinQ" options includes 4 lanes of simultaneous serial data analysis plus the reference lane. If EyeDrII or VirtualProbe are purchased with SDAIII "LinQ" capability, then those capabilities are provided for all four lanes.

Lanescape Comparison Mode

When multiple lanes are enabled for display, Lanescape Comparison Modes is used. Selections for this mode are as follows:

- Single: One lane is displayed at a time.
- · Dual: Two lanes are selected for display.
- · Mosaic: All enabled lanes are displayed

SDAIII "Crosstalk" Capability (Included in SDAIII-Crosstalk and SDAIII-CrossLinQ Options)

In addition to all SDAIII capabilities, "Crosstalk" options add the following noise and crosstalk measurements and analysis tools:

- Total, Random and Deterministic noise (Tn, Rn, Dn) measurements
- · Breakdown of Dn into InterSymbol Interference noise (ISIn) and Periodic noise (Pn)
- · Noise-based eye height and width: EH(BER) and EW(BER)
- Random noise (Rn) + Bounded Uncorrelated noise (BUn) Noise Histogram
- · Q-fit for Noise Histogram
- · Rn+BUn Noise Spectrum and Peak threshold
- · Pn Inverse FFT Plot
- · Rn+BUn Noise Track
- · Crosstalk Eye Contour Plot

SDAIII-CompleteLinQ

The ultimate in serial data single or multi-lane link analysis. Provides all the capabilities mentioned above in SDAIII, "LinQ", and "Crosstalk", and also includes EyeDrII and Virtual Probe capabilities.

Eye Doctor II Advanced Signal Integrity Tools (WM8Zi-EYEDRII)

Complete set of channel emulation, de-embedding and receiver equalization simulation tools. Provides capability to emulate a serial data link, de-embed or embed a fixture, cable or serial data channel, add or remove emphasis, and perform CTLE, FFE, or DFE equalization. If purchased with SDAIII, then capabilities are accessed from within the SDAIII-CompleteLinQ user interface framework.

Virtual Probe Signal Integrity Tools (WM8Zi-VIRTUALPROBE)

Provides ability to define a complex serial data channel or topology with up to six circuit elements that may be embedded or de-embedded, allowing "probing" at a location different than the measured position. If purchased with SDAIII and EyeDrII (or with the EYEDRII-VP or CompleteLinQ options), then capabilities are accessed from within the single SDAIII-CompleteLinQ user interface framework

Software Options (cont'd)

Clock and Clock-Data Timing Jitter Analysis Package (WM8Zi-JITKIT)

Provides convenient setup and four views of jitter (statistical, time, spectrum, and overlaid) for a variety of horizontal, amplitude, and timing parameters. Direct display of jitter measurement values. Supports multiple simultaneous views with fast selection of multiple parameter measurements for fast and easy validation.

Cable De-embedding (WM8Zi-CBL-DE-EMBED) (Standard on SDA 8 Zi-B and DDA 8 Zi-B)

Removes cable effects from your measurements. Simply enter the S-parameters or attenuation data of the cable(s) then all of the functionality of the SDA 8 Zi can be utilized with cable effects de-embedded.

8b/10b Decode (WM8Zi-8B10B D) (Standard on SDA 8 Zi-B and DDA 8 Zi-B)

Intuitive, color-coded serial decode with powerful search capability enables captured waveforms to be searched for user-defined sequences of symbols. Multi-lane analysis decodes up to four simultaneously captured lanes.

Spectrum Analyzer Mode (WM8Zi-SPECTRUM)

This package provides a new capability to navigate waveforms in the frequency domain using spectrum analyzer type controls. FFT capability added to include:

- · Power averaging
- · Freq domain parameters
- Power density
- FFT on up to 128 Mpts
- · Real and image components

Disk Drive Measurements Package (WM8Zi-DDM2) (Standard on DDA 8 Zi-B)

This package provides disk drive parameter measurements and related mathematical functions for performing disk drive WaveShape Analysis. Disk Drive Parameters are as follows:

- amplitude asymmetry
- local base
- local baseline separation
- local maximum
- local minimum
- local number
- local peak-peak
- local time between events
- local time between peaks
- local time between troughs
- local time at minimum - local time at maximum
- local time peak-trough
- local time over threshold

- local time trough-peak
- local time under threshold
- narrow band phase
- narrow band power
- overwrite
- pulse width 50
- pulse width 50 -
- pulse width 50 +
- resolution
- track average amplitude
- track average amplitude -
- track average amplitude +
- auto-correlation s/n
- non-linear transition shift

ORDERING INFORMATION

Product Description	Product Code	Product Description	Product Code
WaveMaster 8 Zi-B Series Oscilloscopes		Included with Standard Configuration	
4 GHz, 40 GS/s, 4ch, 32 Mpts/Ch WaveMaster with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs	WaveMaster 804Zi-B	÷10, 500 MHz Passive Probe (Qty. 4 on 4 – 20 GHz units, Qty. 2 on 25 – 45 GHz units))	
6 GHz, 40 GS/s, 4ch, 32 Mpts/Ch WaveMaster with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs	WaveMaster 806Zi-B	ProLink to SMA Adapter: 4 each (for 4 – 8 GHz units) ProLink to K/2.92 mm Adapter: 4 each (for 13 – 45 GHz un	LPA-SMA-A nits) LPA-K-A
8 GHz, 40 GS/s, 4ch, 32 Mpts/Ch WaveMaster with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs	WaveMaster 808Zi-B	Optical 3-button Wheel Mouse, USB 2.0 Protective Front Cover	
13 GHz, 40 GS/s, 4ch, 32 Mpts/Ch WaveMaster with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs	WaveMaster 813Zi-B	Printed Getting Started Manual	
16 GHz, 80 GS/s, 64 Mpts/Ch DSO with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs. Also operates in 4ch,	WaveMaster 816Zi-B	Anti-virus Software (Trial Version) Microsoft Windows 7 License Commercial NIST Traceable Calibration with Certificate	
40 GS/s, 32 Mpts/Ch mode. 20 GHz, 80 GS/s, 64 Mpts/Ch DSO with 15.3" WXGA Color Display. 50 Ω and 1 MΩ Inputs. Also operates in 4ch,	WaveMaster 820Zi-B	Power Cable for the Destination Country 3-year Warranty	
40 GS/s, 32 Mpts/Ch mode. 25 GHz, 80 GS/s, 64 Mpts/Ch Digital Bandwidth	WaveMaster 825Zi-B	Memory and Sample Rate Options	
Interleaved (DBI) Oscilloscope with 15.3" WXGA Color Display. 50 Ω and 1 MΩ Inputs. Also operates in 20 GHz, 40 GS/s, 4ch, 32 Mpts/Ch mode. 30 GHz, 80 GS/s, 64 Mpts/Ch Digital Bandwidth	WaveMaster 830Zi-B	80 GS/s on 2 Ch Sampling Rate Option for WaveMaster 8 Zi-B (not available for 816Zi-B, 820Zi-B, 825Zi-B or 830Zi-B). Includes two separate external interleaving devices with storage case	WM8Zi-2X80GS
Interleaved (DBI) Oscilloscope with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs. Also operates in 20 GHz,		32 Mpts/Ch Standard Memory for WaveMaster 8 Zi-B. Includes 8 GB of RAM	WM8Zi-STD
40 GS/s, 4ch, 32 Mpts/Ch mode.		64 Mpts/Ch Standard Memory for SDA 8 Zi-B Includes 8 GB of RAM	SDA8Zi-STD
SDA 8 Zi-B Series Serial Data Analyzers 4 GHz, 40 GS/s, 4ch, 64 Mpts/Ch Serial Data Analyzer	CDA 0047; D	64 Mpts/Ch Memory Option for WaveMaster 8 Zi-B	WM8Zi-M-64
with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs,	SDA 804Zi-B	128 Mpts/Ch Memory Option for WaveMaster 8 Zi-B	WM8Zi-L-128
6.5 Gb/s Serial Trigger, 8b/10b and 64b/66b decode.		128 Mpts/Ch Memory Option for SDA 8 Zi-B	SDA8Zi-L-128
6 GHz, 40 GS/s, 4ch, 64 Mpts/Ch Serial Data Analyzer	SDA 806Zi-B	256 Mpts/Ch Memory Option for WaveMaster 8 Zi-B	WM8Zi-VL-256
with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs, 6.5 Gb/s Serial Trigger, 8b/10b and 64b/66b decode.		256 Mpts/Ch Memory Option for SDA 8 Zi-B	SDA8Zi-VL-256
8 GHz, 40 GS/s, 4ch, 64 Mpts/Ch Serial Data Analyzer	SDA 808Zi-B	256 Mpts/Ch Memory Option for DDA 8 Zi-B	DDA8Zi-VL-256
with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs,	SDA 606ZI-D	CPU, Computer and Other Hardware Options	
6.5 Gb/s Serial Trigger, 8b/10b and 64b/66b decode.	ODA 0107' D	GPIB Option for Teledyne LeCroy Oscilloscope.	GPIB-4
13 GHz, 40 GS/s, 4ch, 64 Mpts/Ch Serial Data Analyzer with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs,	SDA 813Zi-B	Half-height Card	
6.5 Gb/s Serial Trigger, 8b/10b and 64b/66b decode.			M8Zi-8-UPG-16GBRAM
16 GHz, 80 GS/s, 128 Mpts/Ch Serial Data Analyzer with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs, 6.5 Gb/s Serial Trigger, 8b/10b and 64b/66b decode.	SDA 816Zi-B	'	M8Zi-8-UPG-32GBRAM
Also operates in 4ch, 40 GS/s, 64 Mpts/Ch mode.		Serial Data and CrossTalk Analysis	CODATITO LILICO
20 GHz, 80 GS/s, 128 Mpts/Ch Serial Data Analyzer with	SDA 820Zi-B	Complete Multi-Lane SDA LinQ WM8Z Framework, including Eve, Jitter, Noise,	i-SDAIII-CompleteLinQ
15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs, 6.5 Gb/s Serial Trigger, 8b/10b and 64b/66b decode. Also operates in 4ch, 40 GS/s, 64 Mpts/Ch mode.		Crosstalk Measurements, with EyeDrII and VirtualProbe	SDA8Zi-CompleteLinQ DDA8Zi-CompleteLinQ
25 GHz,80 GS/s, 128 Mpts/Ch Digital Bandwidth	SDA 825Zi-B		M8Zi-SDA III -CrossLinQ
Interleaved (DBI) Serial Data Analyzer - 15.3" WXGA Color	3DA 02321 B	Framework, Eye, Jitter, Noise and	SDA8Zi-CrossLing
Display. 50 Ω and 1 M Ω Inputs, 6.5 Gb/s Serial Trigger,		Crosstalk Measurements	DDA8Zi-CrossLinQ
and 8b/10b and 64b/66b decode. Also operates in 20 GHz, 40 GS/s, 4ch, 64 Mpts/Ch mode.		Multi-Lane Serial Data Analysis LinQ	WM8Zi-SDA III -LinQ
30 GHz,80 GS/s, 128 Mpts/Ch Digital Bandwidth	SDA 830Zi-B	Framework, Eye and Jitter	SDA8Zi-LinQ
Interleaved (DBI) Serial Data Analyzer - 15.3" WXGA Color	05/10002/15	Measurements	DDA8Zi-LinQ
Display. 50 $\hat{\Omega}$ and 1 M Ω Inputs, 6.5 Gb/s Serial Trigger,			M8Zi-SDA III -Crosstalk
and 8b/10b and 64b/66b decode. Also operates in 20 GHz, 40 GS/s, 4ch, 64 Mpts/Ch mode.		Framework, Eye, Jitter, Noise and	SDA8Zi-Crosstalk
20 0112, 10 00,0, 1011, 0 1 111pts, 011 1110de.		Crosstalk Measurements	DDA8Zi-Crosstalk
DDA 8 Zi-B Series Oscilloscopes		Single-Lane Serial Data Analysis Framework,	WM8Zi-SDA III
6 GHz, 40 GS/s, 4ch, 64 Mpts/Ch Disk Drive Analyzer with	DDA 806Zi-B	Eye and Jitter Measurements PAM4 Signal Analysis	WM8Zi-PAM4
15.3" WXGA Color Display. 50 Ω and 1 MΩ Inputs. 8 GHz. 40 GS/s. 4ch. 64 Mpts/Ch Disk Drive Analyzer with	DDA 808Zi-B	PAIVI4 SIGNALANAIYSIS	VVIVI8ZI-PAIVI4
15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs.		Signal Integrity Toolkits	10 107' \
20 GHz, 80 GS/s, 128 Mpts/Ch Disk Drive Analyzer with 15.3" WXGA Color Display. 50 Ω and 1 M Ω Inputs. Also	DDA 820Zi-B	Advanced De-embedding, Emulation and \text{Virtual Probing Toolkit}	WM8Zi-VIRTUALPROBE
operates in 4ch, 40 GS/s, 64 Mpts/Ch mode.		Signal Integrity Toolkit - Channel & Fixture	WM8Zi-EYEDRII
		De-embedding/Emulation, Tx/Rx Equalization	WW.407; EVEDDILVE
		Bundle - EyeDrll and VirtualProbe Toolkits Cable De-embed Option	WM8Zi-EYEDRII-VP WM8Zi-CBL-DE-EMBED
		'	352 52 2111525
		Modulated Signal Analysis	
		VectorLinQ – Flexible vector signal analysis for	WM8Zi-VECTORLINQ
		electrical signals (RF and baseband I-Q)	MANAOZ: ODTIOAL LUIC
		Optical-LinQ — Coherent optical modulation analysis	WM8Zi-OPTICAL-LINQ

ORDERING INFORMATION

Product Description	Product Code	Product Description	Product Code
High-speed Digital Analyzer Systems		Serial Data Triggers and Decoders	
12.5 GS/s High-speed Digital Analyzer with 18ch QuickLink leadset and LBUS connection	HDA125-18-LBUS	MIL-STD-1553 Trigger and Decode Option MIL-STD-1553 Trigger, Decode, Measure/Graph, ar	WM8Zi-1553 TD nd Eye WM8Zi-1553 TDME
12.5 GS/s High-speed Digital Analyzer with 9ch QuickLink leadset and LBUS connection	HDA125-09-LBUS	Diagram Option 64b/66b Decode Annotation Option	WM8Zi-64b66b D M8Zi-14GBIT-80b-SYMBOL-TD
DDR Debug Tookits			8Zi-UPG-14GBIT-80b-SYMBOL-TD
DDR2 and LPDDR2 Debug Toolkit	WM8ZI-DDR2-TOOLKIT		WM8Zi-6GBIT-80b-SYMBOL-TD
DDR3, DDR3L, LPDDR3, DDR2, and LPDDR2 Debug Toolkit	WM8ZI-DDR3-TOOLKIT	Gbps Serial Trigger option. Also includes 8b/10b and 64b/66b decode. (Standard	
DDR4, DDR3, DDR3L, LPDDR3, DDR2, and LPDDR2 <u>Debug Toolkit</u>	WM8ZI-DDR4-TOOLKIT	on SDA 8 Zi-B.) 8b10b Decode Option	WM8Zi-8B10B D
DDR3, DDR3L, LPDDR3, DDR2, and LPDDR2 Debug Toolkit Upgrade	WM8ZI-UPG-DDR3-TOOLKIT	ARINC 429 Bus Symbolic Decode, WM8Zi- Measure/Graph, and Eye Diagram Option	ARINC429BUS DME SYMBOLIC
DDR4, DDR3, DDR3L, LPDDR3, DDR2, and LPDDR2 Debug Toolkit Upgrade	WM8ZI-UPG-DDR4-TOOLKIT	ARINC 429 Bus Symbolic Decode Option V	VM8Zi-ARINCbus DSYMBOLIC
Cavial Data Camplianas		Audiobus Trigger and Decode for I2S, Option LJ, RJ, and TDM	WM8Zi-Audiobus TD
Serial Data Compliance QualiPHY Enabled 10GBase-KR Software Option	ODLIV 10CDaga VD	Audiobus Trigger, Decode, and Graph Op- tion for I2S, LJ, RJ, and TDM	WM8Zi-Audiobus TDG
QualiPHY Enabled 10GBase-RR Software Option QualiPHY Enabled 10GBase-T Software Option	QPHY-10GBase-KR QPHY-10GBASE-T	CANbus FD Trigger and Decode Option	WM8Zi-CAN FDbus TD
QualiPHY Enabled BroadR-Reach Software Option	QPHY-BroadR-Reach		7i-CAN FDbus TDM SYMBOLIC
QualiPHY Enabled DDR2 Software Option	QPHY-DDR2	Measure/Graph Option	EL CANAL DEGLE LEIN CAMBOLIO
QualiPHY Enabled DDR3 Software Option	QPHY-DDR3	CAN FD Trigger, Decode, Measure/Graph,	WM8Zi-CAN FDBUS TDME
QualiPHY Enabled DDR4 Software Option	QPHY-DDR4	and Eye Diagram Option	CAN EDDI IO TOME OVA ADOLLO
QualiPHY Enabled DisplayPort Software Option QualiPHY Enabled Embedded DisplayPort Software Option	QPHY-DisplayPort	Decode, and Measure/Graph, and Eye	i-CAN FDBUS TDME SYMBOLIC
QualiPHY Enabled Embedded DisplayPort Software C		Diagram Option CANbus TD Trigger and Decode Option	WM8Zi-CANbus TD
QualiPHY Enabled HDMI 1.4 and HDMI 2 Software O		CAN Trigger, Decode, Measure/Graph, and	WM8Zi-CANBUS TDME
QualiPHY Enabled LPDDR2 Software Option	QPHY-LPDDR2	Eye Diagram Option	WINDER OF TURBER
QualiPHY Enabled MIPI D-PHY Software Option	QPHY-MIPI-DPHY	CAN Symbolic Trigger, Decode, and WM8	BZI-CANBUS TDME SYMBOLIC
QualiPHY Enabled MIPI M-PHY Software Option	QPHY-MIPI-MPHY	Measure/Graph, and Eye Diagram Option	W 107' D' DE001 D
QualiPHY Enabled MOST50 ePHY Software Option	QPHY-MOST50	DigRF 3G Decode Option DigRF v4 Decode Option	WM8Zi-DigRF3Gbus D
QualiPHY Enabled MOST150 oPHY Software Option	QPHY-MOST150	MIPI D-PHY Decode Option	WM8Zi-DigRFv4bus D WM8Zi-DPHYbus D
QualiPHY Enabled PCIe 3.0 Software Option	QPHY-PCIe3	MIPI D-PHY Decode option MIPI D-PHY Decode and Physical Layer	WM8Zi-DPHYbus DP
QualiPHY Enabled PCIe Gen1 Software Option	QPHY-PCle	Test Option	
QualiPHY Enabled SATA Software Option	QPHY-SATA-TSG-RSG	I ² C, SPI, UART-RS232 Trigger and Decode Bundle	WM8Zi-EMB TD
QualiPHY Enabled SAS-2 Software Option	QPHY-SAS2	I ² C, SPI, UART-RS232 Trigger, Decode, Measure/Graph, and Eye Diagram Bundle	WM8Zi-EMB TDME
QualiPHY Enabled SAS-3 Software Option	QPHY-SAS3	Ethernet 10G Decode Option	WM8Zi-ENET10Gbus D
QualiPHY Enabled SFI Software Option	QPHY-SFI	ENET Decode Option	WM8Zi-ENETbus D
QualiPHY Enabled USB 2.0 Software Option	QPHY-USB [‡]	Fibre Channel Decode Annotation Option	WM8Zi-FCbus D
QualiPHY Enabled USB 3.0 Transmitter/ Receiver Co pliance Software Option	m- QPHY-USB3-Tx-Rx	FlexRay Trigger and Decode Option	WM8Zi-FlexRaybus TD
QualiPHY Enabled USB 3.1 Transmitter/ Receiver Copliance Software Option	m- QPHY-USB3.1-Tx-Rx	FlexRay Trigger, Decode, Measure/Graph and Physical Layer Option	WM8Zi-FLEXRAYBUS TDMP
*TF-ENET-B required. [†] TF-HDMI-3.3V-QUADPAK requi		I ² C Bus Trigger and Decode Option	WM8Zi-I2Cbus TD
PCI Express, SuperSpeed USB (USB 3.0) and SATA Comp Solutions are available. Consult Factory.	lete Hardware/Software Test	I ² C Trigger, Decode, Measure/Graph, and Eye Diagram Option LIN Trigger and Decode Option	WM8Zi-I2CBUS TDME
0 : 10 : T : 5: :		LIN Trigger and Decode Option LIN Trigger. Decode. Measure/Graph, and	WM8Zi-LINbus TD WM8Zi-LINBUS TDME
Serial Data Test Fixtures		Eye Diagram Option	WIVIOZI-LINBOS I DIVIL
Test Fixture for 10GBase-T	TF-10GBASE-T	Manchester Decode Option	WM8Zi-Manchesterbus D
10/100/1000Base-T Ethernet Test Fixture Telecom Adapter Kit 100 Ω Bal., 120 Ω Bal., 75 Ω Unl	TF-ENET-B*	MIPI M-PHY Decode Option	WM8Zi-MPHYbus D
HDMI 50Ω Pull-Up Terminator	pal. TF-ET TF-HDMI-3.3V	MIPI M-PHY Decode and Physical Layer Test Option	
HDMI Pull-Up Terminator Quad Pack	TF-HDMI-3.3V-QUADPAK	MS-500-36 with I2C, SPI, UART and RS-232 Trigger and Decodes Bundle	WM8Zi-MSO-EMB TD
SATA 1.5 Gb/s. 3.0 Gb/s and 6.0 Gb/s	TF-SATA-C	MS-500-36 with I2C, SPI, UART-RS-232 Trig,	WM8Zi-MSO-EMB TDME
Compliance Test Fixture SATA 1.5 Gb/s, 3.0 Gb/s and 6.0 Gb/s	TE CATA O KIT	Decode, Measure/Graph and Eye Bundle	\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\
Compliance Test Fixture Measure Kit	TF-SATA-C-KIT	PCI Express Gen1 Decode Option	WM8Zi-PClebus D
USB 2.0 Compliance Test Fixture	TF-USB-B	PROTObus MAG Serial Debug Toolkit Decode Annotation and Protocol	WM8Zi-PROTObus MAG WM8Zi-ProtoSync
USB 3.0 and 3.1 Compliance Test Fixture	TF-USB3	Analyzer Synchronization Software Option	WWWSZFFTOLOGYTIC
2 x BNC to SMA Adapter	ENET-2ADA-BNCSMA	Decode Annotation and Protocol Analyzer+Bit	WM8Zi-PROTOSYNC-BT
2 x 18 inch SMA to SMA Cable	ENET-2CAB-SMA018	Tracer SW Synchronization Option	
2 x 36 inch SMA to SMA Cable	ENET-2CAB-SMA036	SAS Decode Annotation Option	WM8Zi-SASbus D
100 ps Rise Time Filter	RISE-TIME-FILTER-100PS	SATA Decode Annotation Option	WM8Zi-SATAbus D
150 ps Rise Time Filter	RISE-TIME-FILTER-150PS	SENT Bus Decode Option SpaceWire Decode Option	WM8Zi-SENTbus D WM8Zi-SpaceWirebus D
20 dB SMA Attenuators	20DB-SMA-ATTENUATOR	SPI Bus Trigger and Decode Option†	WM8Zi-SPIbus TD
*Includes ENET-2CAB-SMA018 and ENET-2ADA-BNCSM	4	SPI Trigger, Decode, Measure/Graph, and	WM8Zi-SPIBUS TDME
		Eye Diagram Option	

ORDERING INFORMATION

Product Description	Product Code
Serial Data Triggers and Decoders	
SPMI Decode Option	WM8Zi-SPMIbus D
UART and RS-232 Trigger and Decode Option	WM8Zi-UART-RS232bus TD
UART-RS232 Trigger, Decode, Measure/Graph, and Eye Diagram Option	WM8Zi-UART-RS232BUS TDME
MIPI UniPro Protocol Decoder	WM8Zi-UNIPRObus D
USB2-HSIC Decode Option	WM8Zi-USB2-HSICbus D
USB 2.0 Decode Option	WM8Zi-USB2bus D
USB 2.0 Decode, Measure/Graph, and Eye Diagram Option	WM8ZI-USB2BUS DME
USB 3.0 Decode Annotation Option	WM8Zi-USB3bus D
High-speed Digitizer Output	
High-speed PCIe Gen1 x4 Digitizer Output	LSIB-1
PCI Express x1 Host Interface Board for Desktop	PC LSIB-HOSTBOARD
PCI Express x1 Express Card Host Interface for Laptop Express Card Slot	LSIB-HOSTCARD
PCI Express x4 3-meter Cable	LSIB-CABLE-3M

with x4 Cable Connectors Included Mixed Signal Testing Options

with x4 Cable Connectors Included PCI Express x4 7-meter Cable

MS-500
MS-500-36
MS-250

LSIB-CABLE-7M

General Purpose and Application Specific Software Options

ocherar i ar pose and Application opecine of	itware options
Spectrum Analysis Option	WM8Zi-SPECTRUM
Coherent Optical Analysis Software	WM8ZI-OPTICAL-LINQ
Digital Filter Software Package	WM8Zi-DFP2
Serial Data Mask Software Package	WM8Zi-SDM
Disk Drive Measurements Software Package	WM8Zi-DDM2
Disk Drive Analyzer Software Package	WM8Zi-DDA
Advanced Optical Recording Measurement Package	WM8Zi-BORM
Electrical Telecom Mask Test Software Package	WM8Zi-ET-PMT
EMC Pulse Parameter Software Package	WM8Zi-EMC
Power Analysis Option	WM8Zi-PWR
Clock Jitter Analysis with Four Views Software Package	WM8Zi-JITKIT

General Accessories

Keyboard, USB	KYBD-1
Probe Deskew and Calibration Test Fixture	TF-DSQ
Hard Carrying Case	WM8Zi-HARDCASE
Soft Carrying Case	WM8Zi-SOFTCASE
Rackmount Accessory for WM8Zi	WM8Zi-RACKMOUNT
ProLink to SMA Adapter	LPA-SMA-A
Kit of ProLink to SMA Adapters	LPA-SMA-KIT-A
ProLink to K/2.92 mm Adapter	LPA-K-A
Kit of ProLink to K/2.92 mm Adapters	LPA-K-KIT-A
Oscilloscope Cart with Additional Shelf and Drawer	OC1024-A
Oscilloscope Cart	OC1021-A
Oscilloscope Cart	OC1021-

Prohes and Prohe Accessories

Product Description

Probes and Probe Accessories	
High Voltage Fiber Optic Probe, 60 MHz Bandwidth.	HVF0103
Power/Voltage Rail Probe. 4 GHz bandwidth, 1.2x attenuation, +/-30V offset, +/-800mV	RP4030
1.0 GHz, 0.9 pF, 1 MΩ High Impedance Active Probe	ZS1000
1.5 GHz, 0.9 pF, 1 MΩ High Impedance Active Probe	ZS1500
2.5 GHz, 0.9 pF, 1 MΩ High Impedance Active Probe	ZS2500
4.0 GHz, 0.6 pF, 1 MΩ High Impedance Active Probe	ZS4000
200 MHz, 3.5 pF, 1 MΩ Active Differential Probe	ZD200
25 MHz High Voltage Differential Probe	HVD3102
1kV, 25 MHz High Voltage Differential Probe without tip Accessories	HVD3102-NOACC
120 MHz High Voltage Differential Probe	HVD3106
1kV, 120 MHz High Voltage Differential Probe without tip Accessories	HVD3106-NOACC
80 MHz, High Voltage Differential Probe with 6m cable	HVD3106-6M
2kV, 120 MHz High Voltage Differential Probe	HVD3206
2kV, 80 MHz High Voltage Differential Probe with 6m cable	HVD3206-6M
6kV, 100 MHz High Voltage Differential Probe	HVD3605
500 MHz, 1.0 pF Active Differential Probe, ±8 V	ZD500
1 GHz, 1.0 pF Active Differential Probe, ±8 V	ZD1000
1.5 GHz, 1.0 pF Active Differential Probe, ±8 V	ZD1500
WaveLink 4 GHz 2.5 Vp-p Differential Probe System	D410-A-PS
WaveLink 4 GHz 5 Vp-p Differential Probe System	D420-A-PS
WaveLink 6 GHz 2.5 Vp-p Differential Probe System	D610-A-PS
WaveLink 6 GHz 5 Vp-p Differential Probe System	D620-A-PS
WaveLink 8 GHz 3.5Vp-p Differential Probe System	D830-PS
WaveLink 10 GHz 3.5Vp-p Differential Probe System	D1030-PS
WaveLink 13 GHz 3.5Vp-p Differential Probe System	D1330-PS
WaveLink 13 GHz, 2.0 Vp-p Differential Probe System	D1305-A-PS
WaveLink 16 GHz, 2.0 Vp-p Differential Probe System	D1605-A-PS
WaveLink 20 GHz, 2.0Vp-p Differential Probe System	D2005-A-PS
WaveLink 25 GHz, 2.0 Vp-p Differential Probe System	D2505-A-PS
WaveLink 4 GHz Differential Amplifier Module with Adjustable Tip	D400A-AT†
WaveLink 6 GHz Differential Amplifier Module with Adjustable Tip	D600A-AT*
WaveLink ProLink Platform/Cable Assembly (4 – 6 GHz)	WL-PLink-CASE
WaveLink ProBus Platform/Cable Assembly (4 GHz)	WL-PBus-CASE
SMA/SMP Lead Set for Dxx30 Probes Dxx	30-SMA-SMP Leads
Optical-to-Electrical Converter, DC to 9.5 GHz, 785 to 1550 nr	n OE695G
Optical-to-Electrical Converter,	OE6250G-M
DC to 36 GHz, 830 to 1600nm	
7.5 GHz Low Capacitance Passive Probe (\div 10, 1 k Ω ; \div 20, 500	OΩ) PP066
TekProbe to ProBus Probe Adapter	TPA10

- * For a complete probe, order a WL-PLink-CASE Platform/Cable Assembly with the Adjustable Tip Module.
- † For a complete probe, order a WL-PBUS-CASE Platform/Cable Assembly with the Adjustable Tip Module

A variety of other active voltage and current probes are also available. Consult Teledyne LeCroy for more information.

Customer Service

Teledyne LeCroy oscilloscopes and probes are designed, built, and tested to ensure high reliability. In the unlikely event you experience difficulties, our digital oscilloscopes are fully warranted for three years and our probes are warranted for one year.

This warranty includes:

- No charge for return shipping
- Long-term 7-year support
- Upgrade to latest software at no charge



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